



МОСКОВСКИЙ ИНЖЕНЕРНО-ФИЗИЧЕСКИЙ ИНСТИТУТ
(ГОСУДАРСТВЕННЫЙ УНИВЕРСИТЕТ)

SiPMs: parameters and applications

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DITANET

December 5-7 2011 DESY

Homage of Boris Dolgoshein (1930-2010)



Professor MEPHI

Head of the particle-physics department
of MEPHI

Inventor of streamer chamber (1962)
Developer and pioneer of Transition
Radiation Detector (TRD)

Since 1993 Boris developed a new
photon detector which he called Silicon
PhotoMultiplier (SiPM) in collaboration
with DESY and then with Max Planck
Institute fur Physics

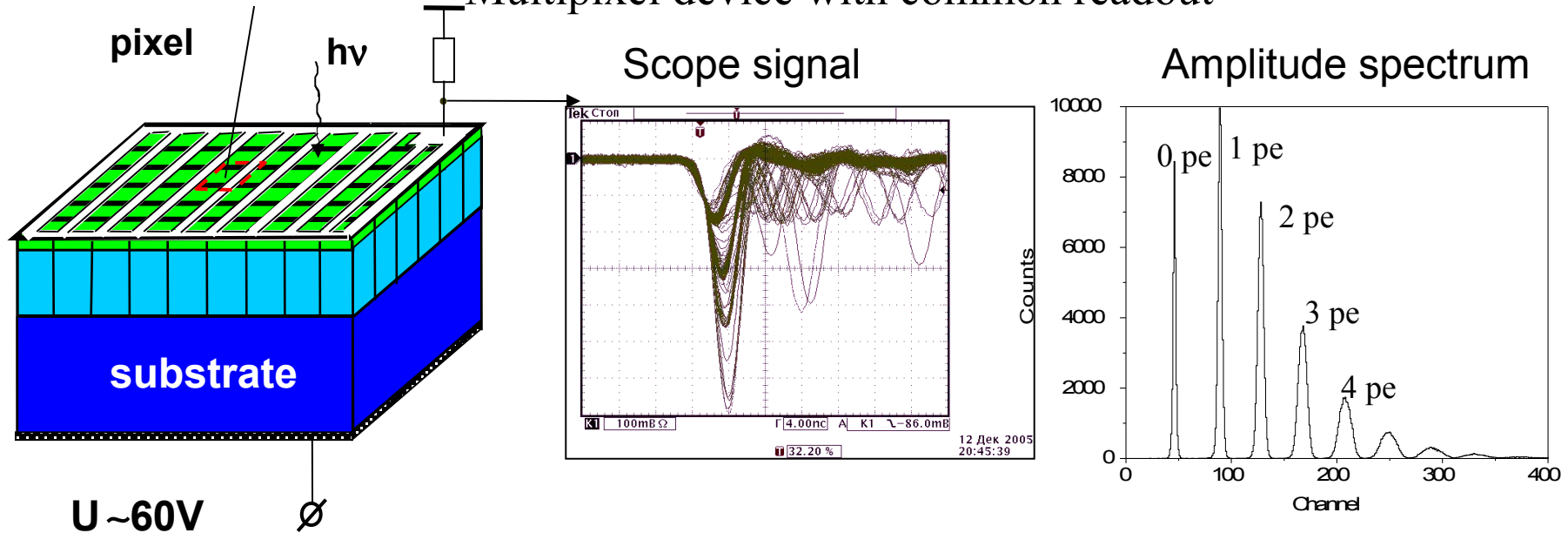
Outline

- What is it – SiPM?
- SiPM main parameters
- Parameters sensitivity
- Manufacturers and experiments
- Radiation hardness
- Electronics
- Summary

Silicon Photomultiplier (SiPM)

The novel type of photon's detector

Multipixel device with common readout



SiPM - main features:

- Each pixel – p-n-junction in selfquenching Geiger mode
- Pixels number: $\sim 1000/mm^2$
- All pixels are equal
- Pixels are independent from each other
- Signal – is sum of all fired pixels



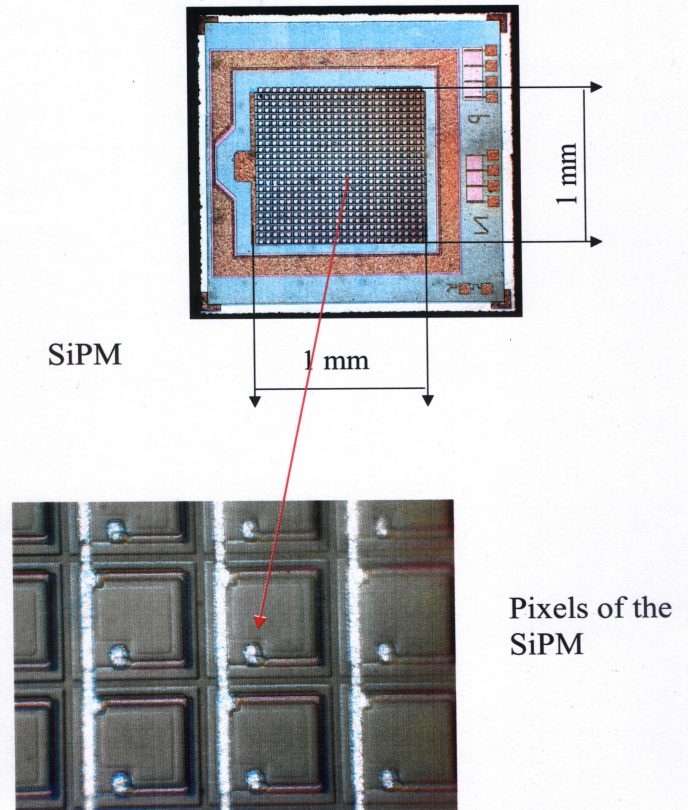
**Pixel signal - 0 or 1
But SiPM is analogue
device**

Silicon Photomultiplier (SiPM)

SiPM – main features:

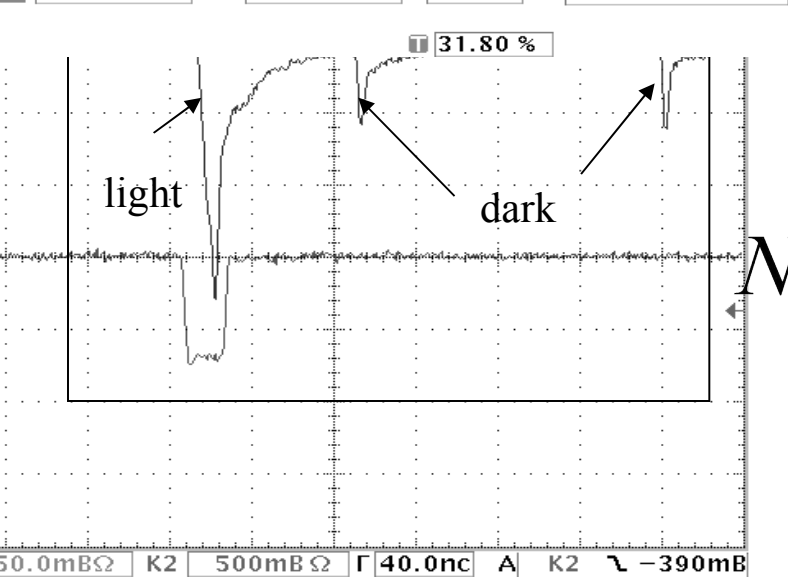
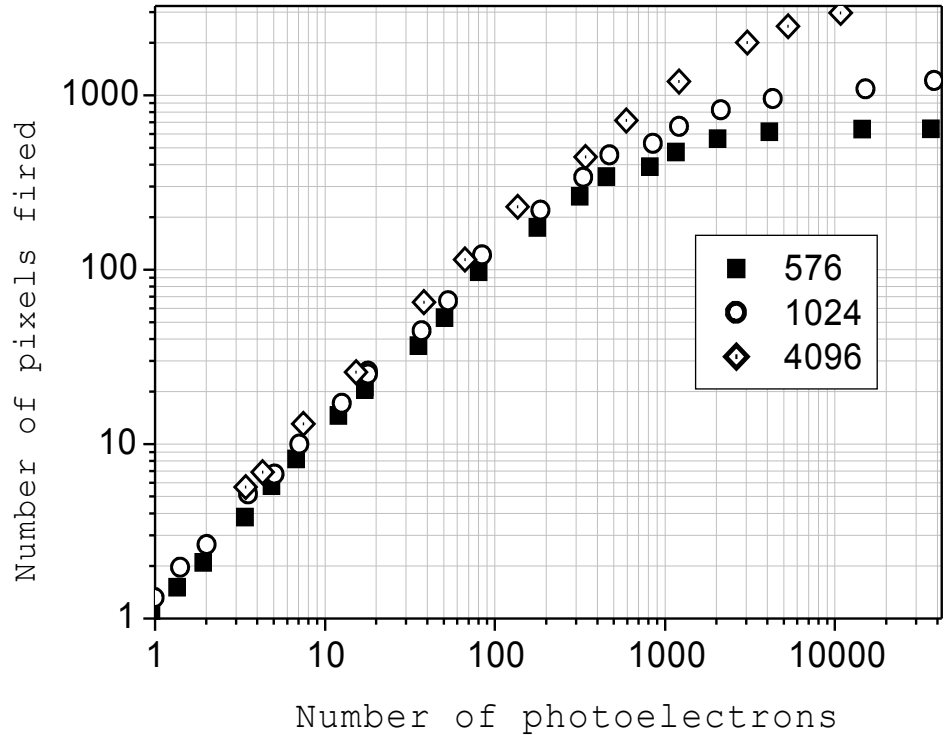
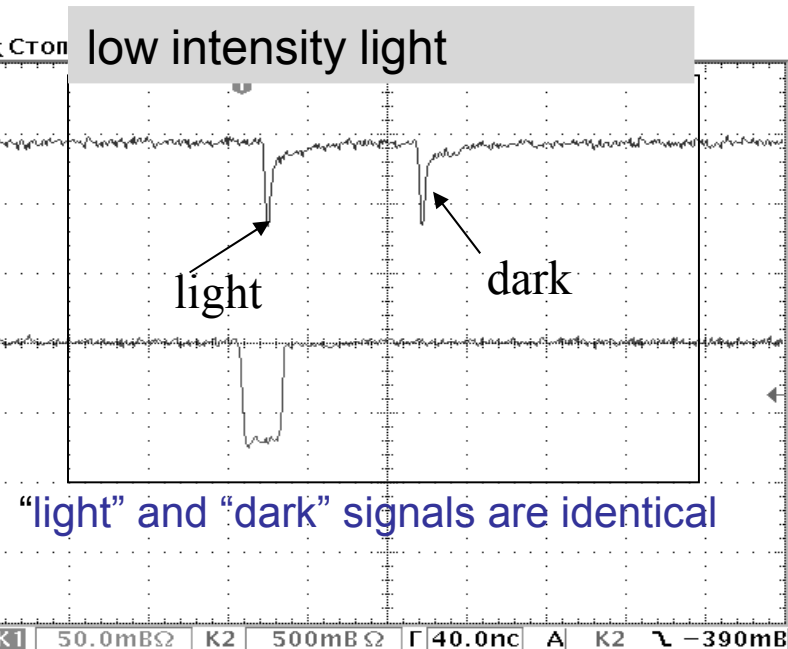
- Sensitivity to single photons
 - Possibility to measure light intensity
 - Excellent amplitude resolution
 - Negligible nuclear counting effect
 - Immunity to magnetic fields up to 7 T
- 2008 IEEE Nuclear Science Symposium Conference Record
Performance Evaluation of SiPM Detectors for PET
Imaging in the Presence of Magnetic Fields S.España, et al.
- Compactness
 - Low weight
 - Low power consumption ($\sim 50\mu\text{W}$)
 - Low voltage supply (20-100V)
 - Fast signal (~ 1 ns front)
 - Simple FE electronics
 - Room temperature operation

Microphotography of the SiPM



Silicon Photomultiplier (SiPM)

Response function for SiPMs with different pixel numbers



$$N_{firedcells} = N_{total} \cdot \left[1 - e^{-\frac{N_{photon} \cdot PDE}{N_{total}}} \right]$$

umber of pixels inside SiPM

Silicon Photomultiplier (SiPM)

Around 1990 the initial prototypes of SiPM (**MRS** Metal- Resistor Semiconductor APD's) were invented in Russia
(*V. Golovin, Z. Sadygov, N. Yusipov (Russian patent #1702831, from 10/11/1989)*)

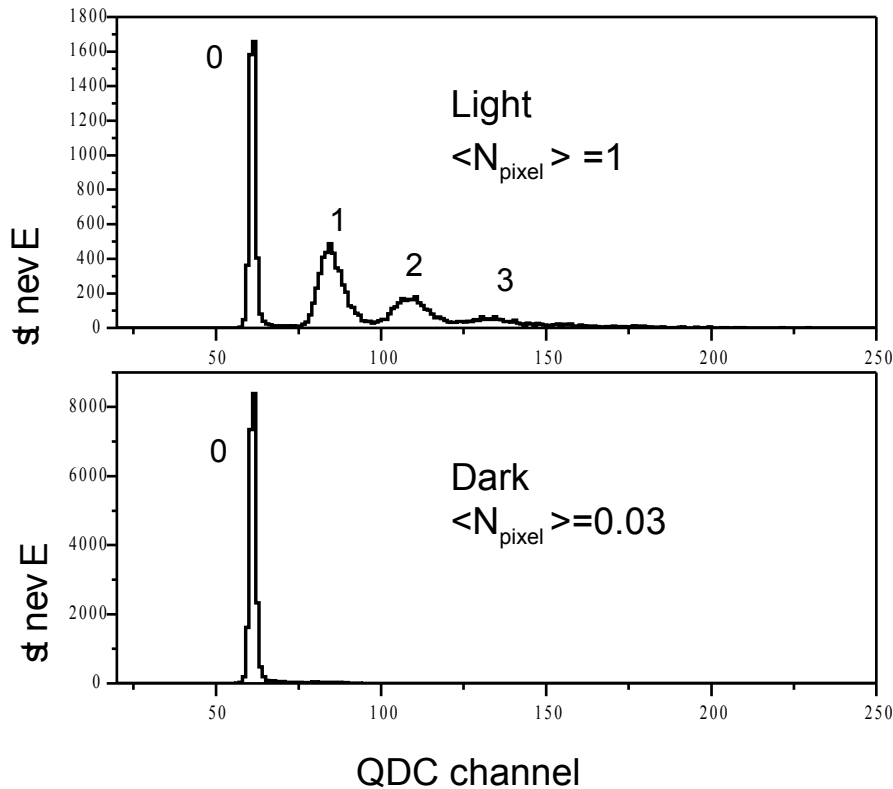
They had :

- Too difficult and unreproducible technology
- Too low light detection efficiency (of about 1%)
- Unclear operational principle

But nevertheless they look very promising detectors for Experimental Physics!

- Department of Elementary Particles headed by prof. Dolgoshein at MEPHI started to investigate such devices since 1993
- Since 2009 MEPHI together with MPI for Physics (Munich) have licence/collaboration agreement with Excelitas (former Perkin-Elmer) and develop new advanced detectors for different kinds of applications

Main SiPM's parameters



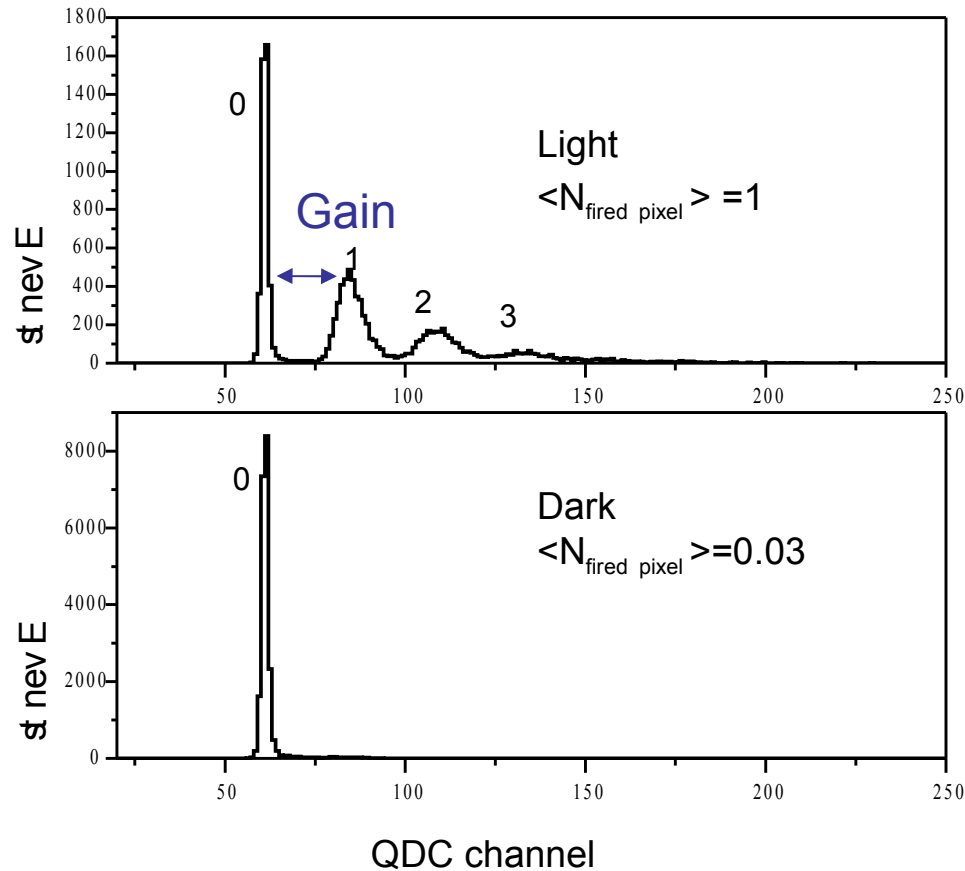
SiPM's single pixel spectra is very useful thing! There are allow us to determine almost all main SiPM parameters.

Quite important – PDE, gain and xt (ap) are measured independently

- Photon Detection Efficiency **PDE**
- Gain **G**
- Crosstalk **xt**
- Afterpulsing **ap**
- Dark rate **f**

- Pixel's recovery time τ
- Intrinsic jitter σ_t

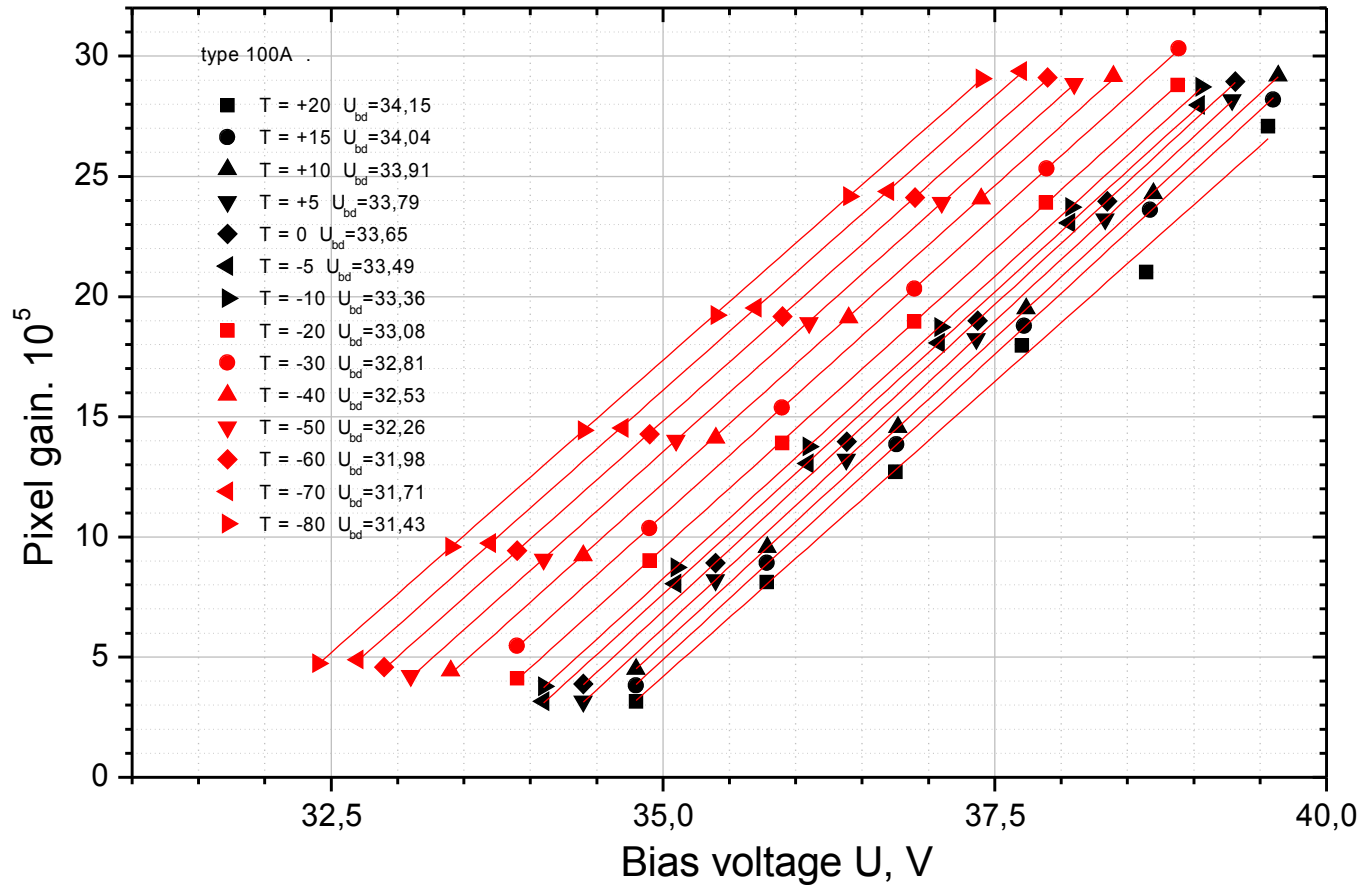
Main SiPM's parameters. Gain



$$G = \frac{C_{\text{pixel}} \cdot (U - U_{\text{breakdown}})}{q}$$

We need to collect SiPM's spectra for different voltages

Main SiPM's parameters. Gain for different Temperature



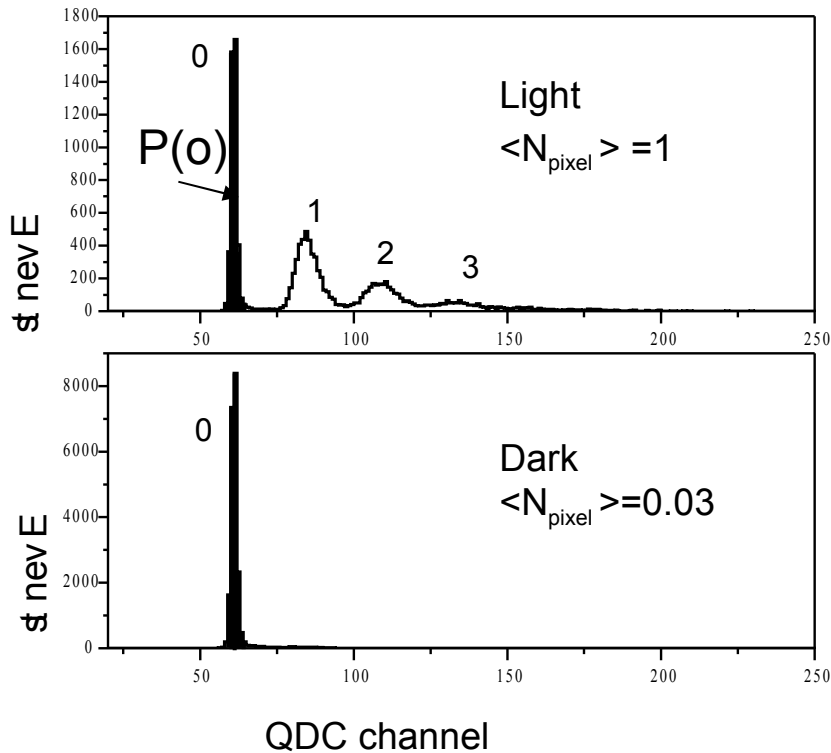
$U_{breakdown} \rightarrow G=0$

Overvoltage $\Delta U = U - U_{breakdown}$

ΔU and $U_{breakdown}$ – are needed for different type SiPM comparison

With temperature decreasing $U_{breakdown}$ decreases too – temperature sensitivity

Main SiPM's parameters. PDE



$$PDE = \frac{\langle N_{\text{fired_pixel}} \rangle}{\langle N_{\text{photons}} \rangle}$$

$\langle N_{\text{photons}} \rangle$ - we need a calibrated photodetector

For $\langle N_{\text{fired_pixel}} \rangle$ assume Poisson distribution of photons:

$$P(n, \lambda) = \frac{\lambda^n e^{-\lambda}}{n!}$$

We can find $\langle N_{\text{pixel}} \rangle$ from “zero” peak probability:

$$P(0, \langle N_{\text{pixel}} \rangle) = e^{-\langle N_{\text{pixel}} \rangle}$$

It means that true number of initially fired pixels from light pulse which is free from crosstalk and afterpulsing can be determined as:

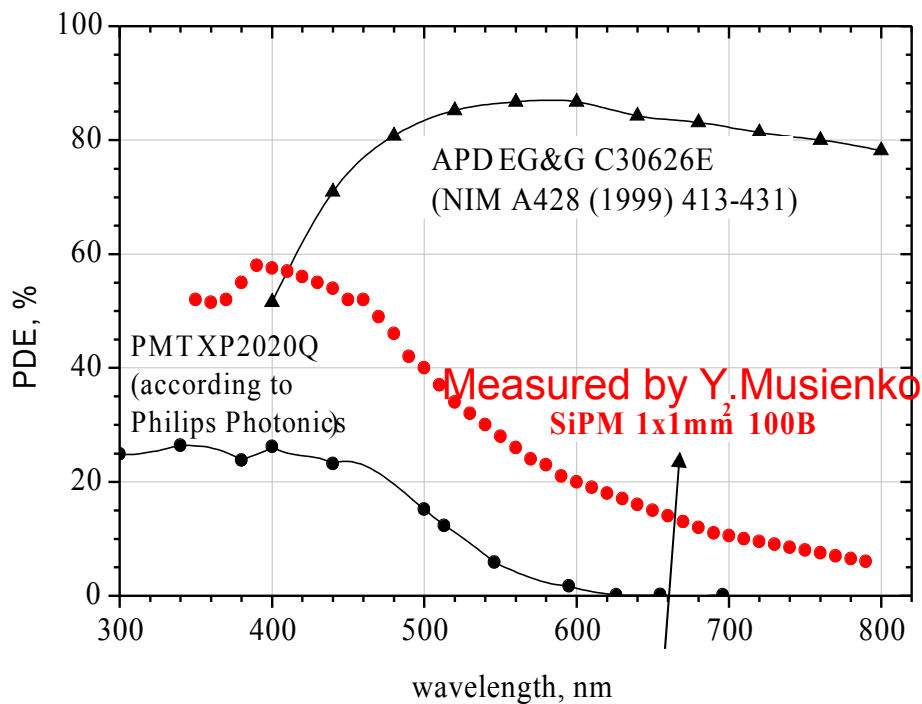
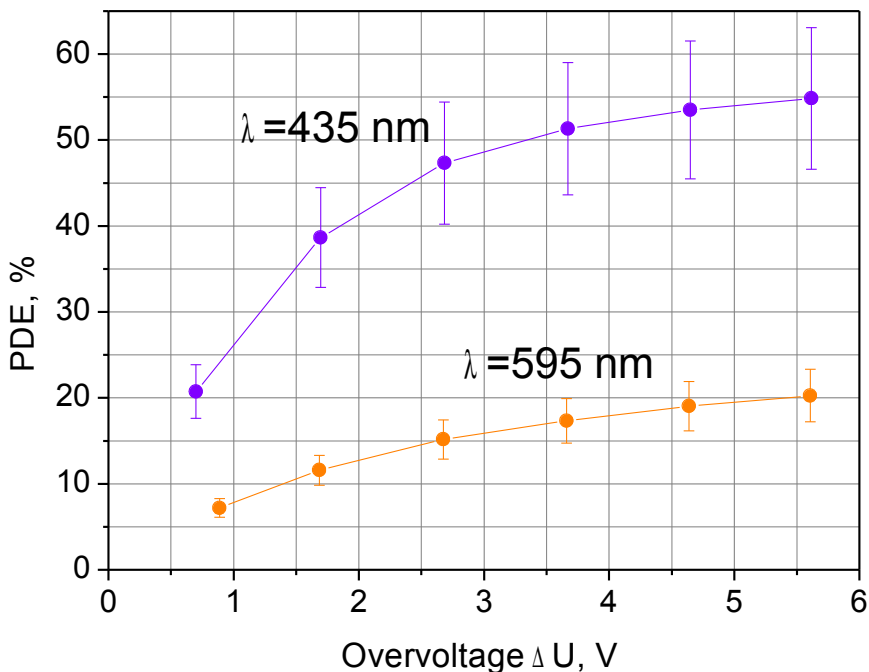
$$\langle N_{\text{fired_pixel}} \rangle = -\ln\left(\frac{S_{\text{ped_light}}}{S_{\text{total_light}}}\right) + \ln\left(\frac{S_{\text{ped_dark}}}{S_{\text{total_dark}}}\right)$$

Main SiPM's parameters. PDE

Spectral PDE for latest MEPhi/MPI SiPM produced in cooperation with Excelitas

100 micron pixel size, geometrical efficiency 80%

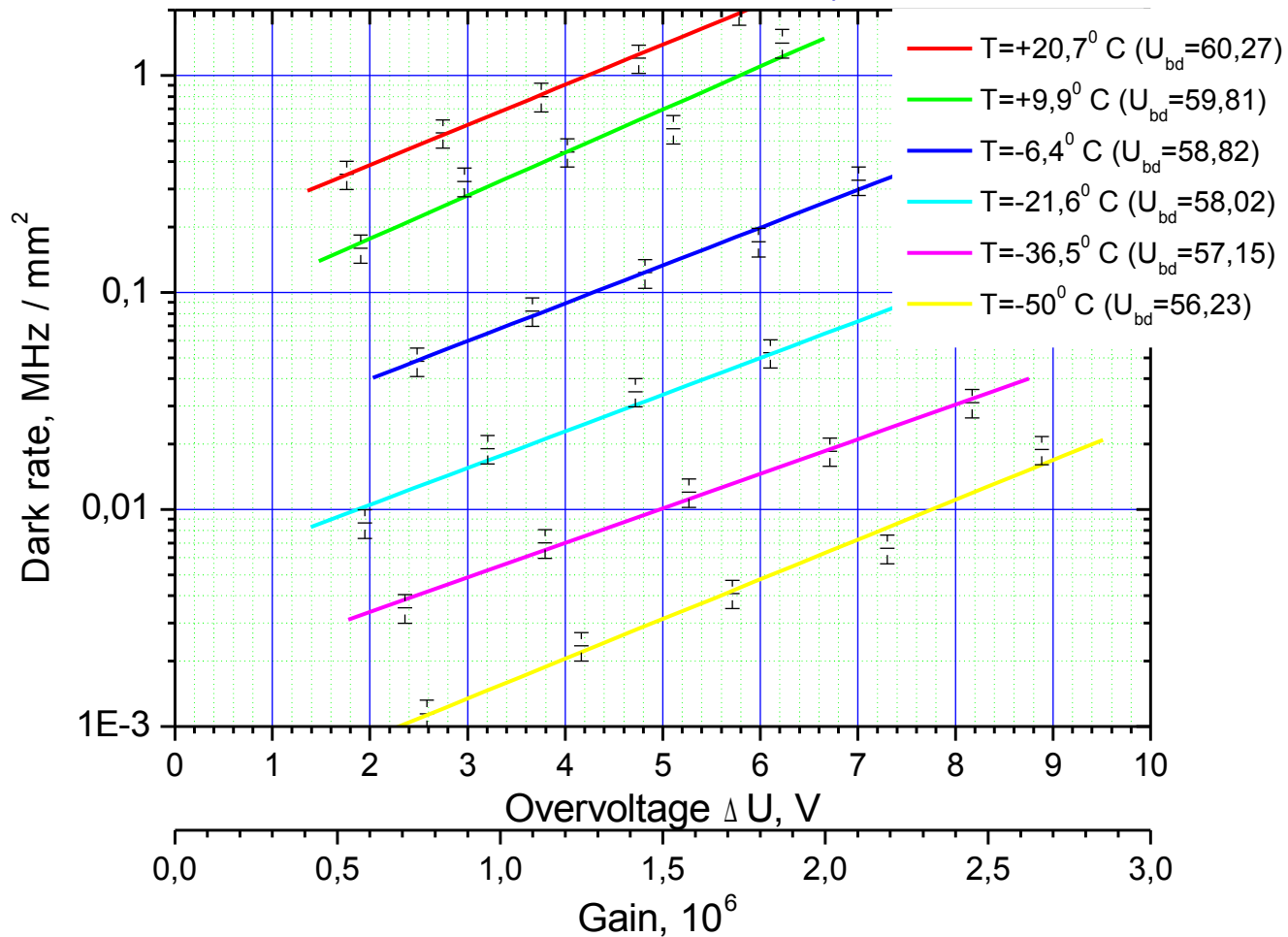
MEPhi measurements



Yury Musienko (louri.Musienko@cern.ch)

Main SiPM's parameters. Dark rate

SiPM 1x1 mm² , 10³ pixels



→ DR typically 10⁶ 1/mm² (room T)

→ Cooling helps(-50 C)

→ DR increases with overvoltage(tunneling)->deep cooling doesn't help!

Pixel recovery time

- The time needed to recharge a cell after a breakdown depends mostly on the cell size (C_{pix}) and the quenching resistor (R_q).

Recovery time of **SINGLE** pixel:

τ

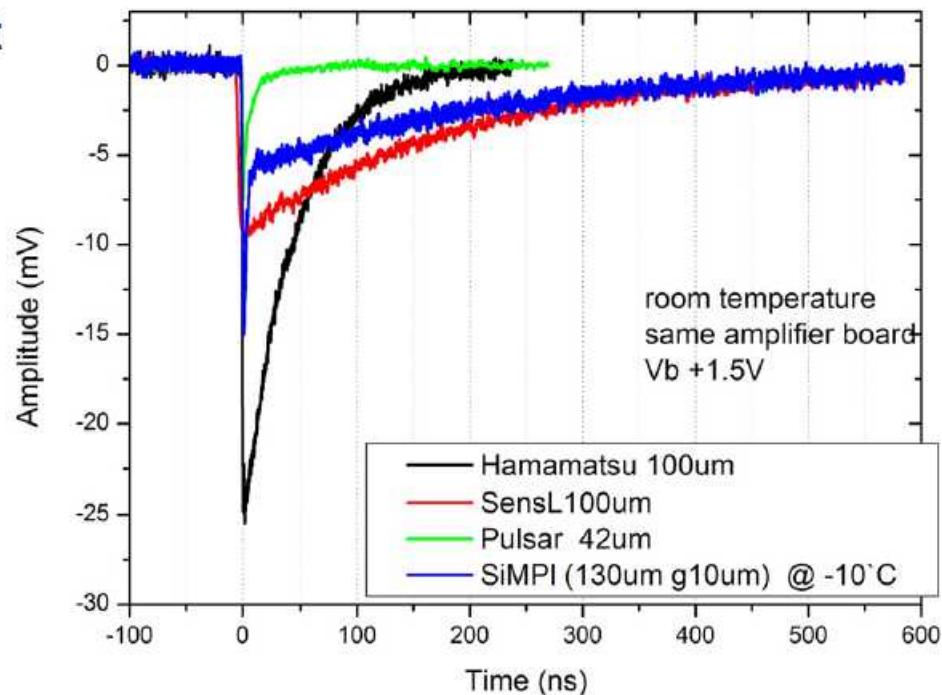
typical values: $R_q \sim 0.5\text{-}20\text{M}\Omega$, $C_{pix} \sim 20\text{-}150\text{fF}$

$R_q C_{pix} \tau \sim 20\text{ns} - \text{few } \mu\text{s}$

! Polysilicon resistors are T dependent

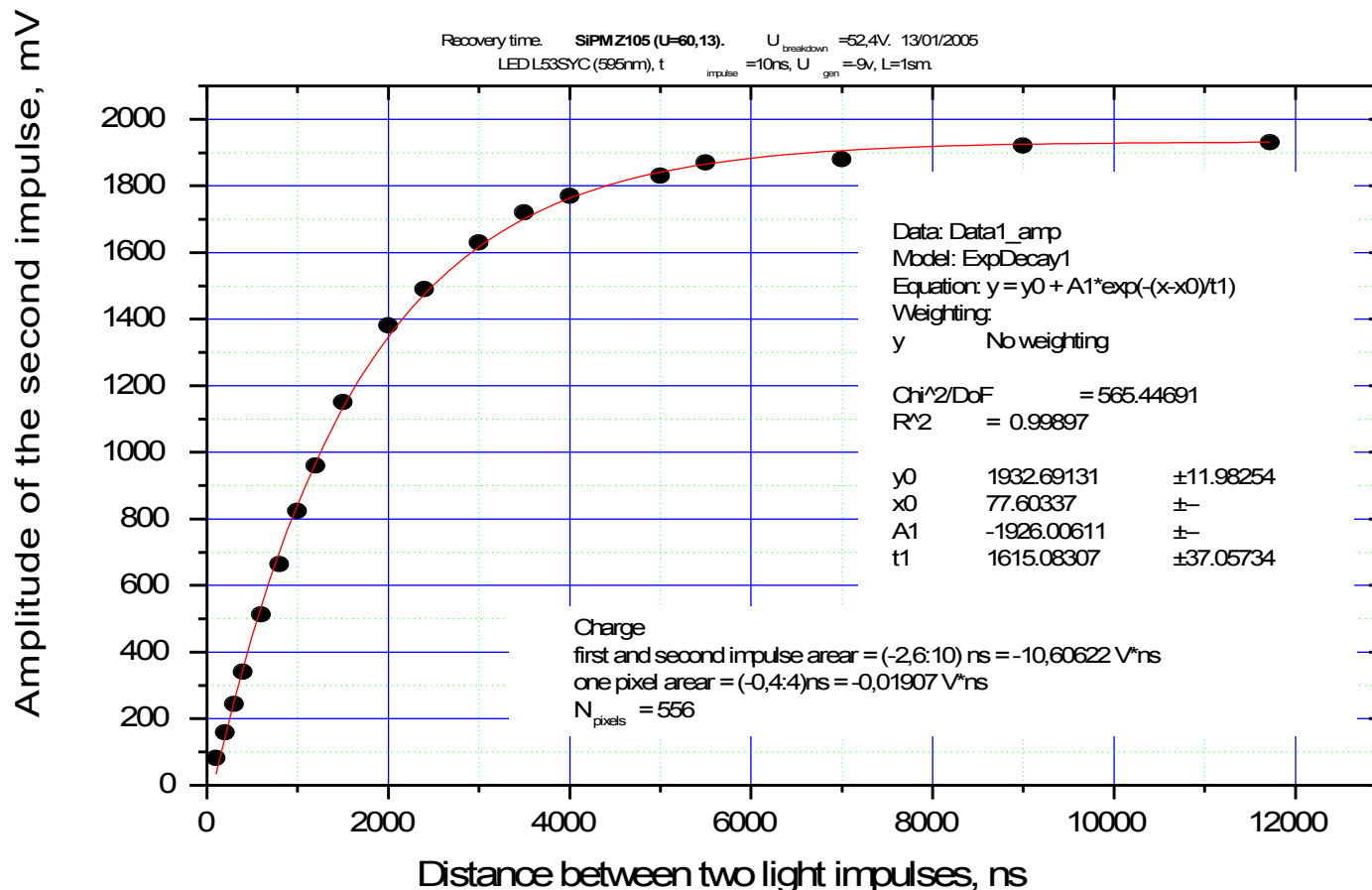
→ favor high resistivity metal alloy

Important for design of readout electronics: Integration or shaping time has to match SiPM signal length, otherwise loss of gain



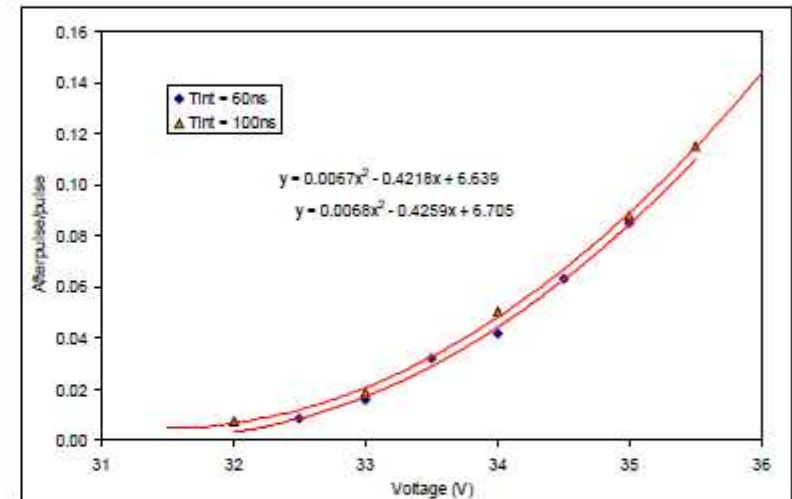
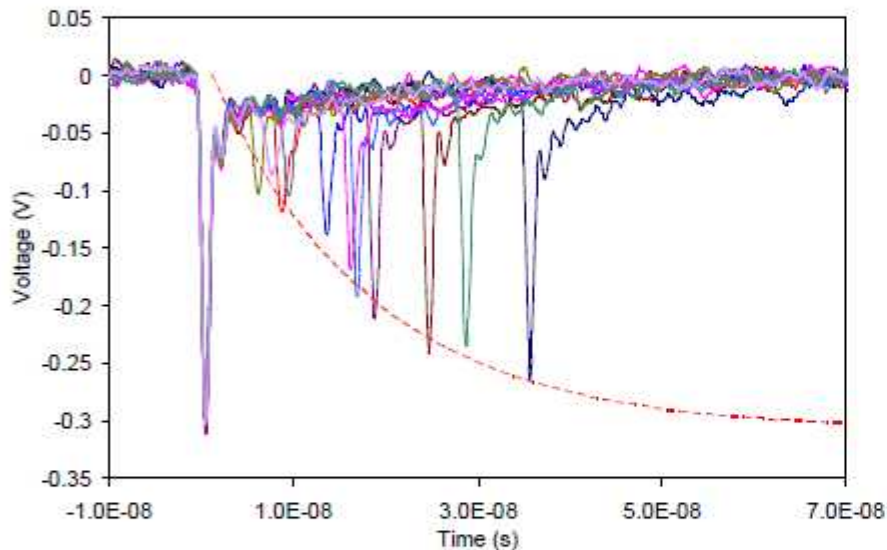
Main SiPM's parameters. Recovery time

Double light pulse method. Possible to use for single pixel and for SiPM itself. Comparison of second pulse SiPM amplitude with first one in dependence from time interval between pulses



After-pulsing

Another problem: carriers trapped during the avalanche discharge and then released trigger a new avalanche during a period of several 100 ns after the breakdown



Events with after-pulse measured on a single micropixel.

After-pulse probability increases with the bias

(C. Piemonte: June 13th, 2007, Perugia)

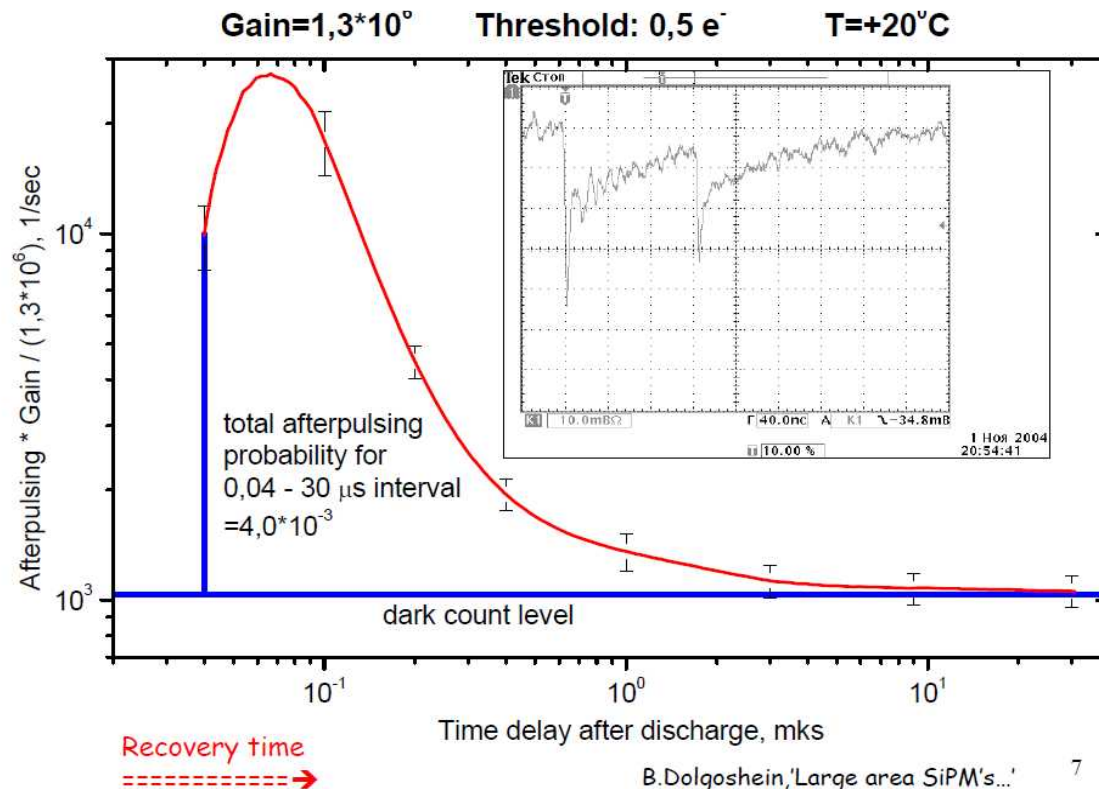
Solutions: "cleaner" technology, longer pixel recovery time and **smaller gain**

Main SiPM's parameters. Afterpulsing

4th NDIP, Beaune-2005

“Large area Silicon
Photomultipliers:
Performance and
Applications”

B.Dolgoshein, MEPHI

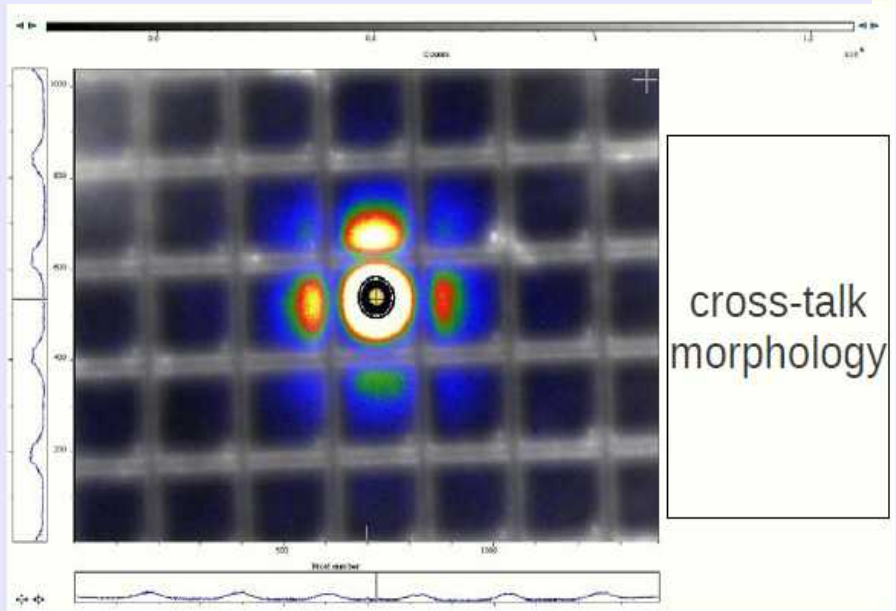
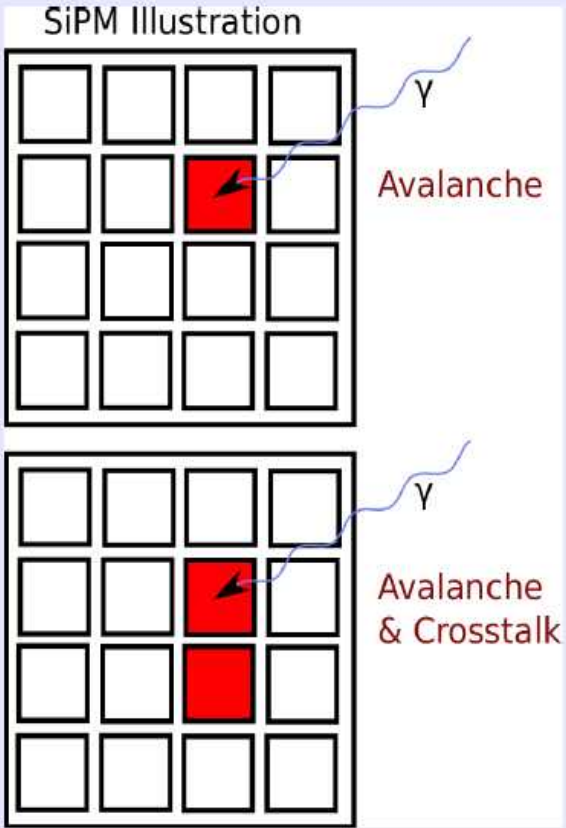
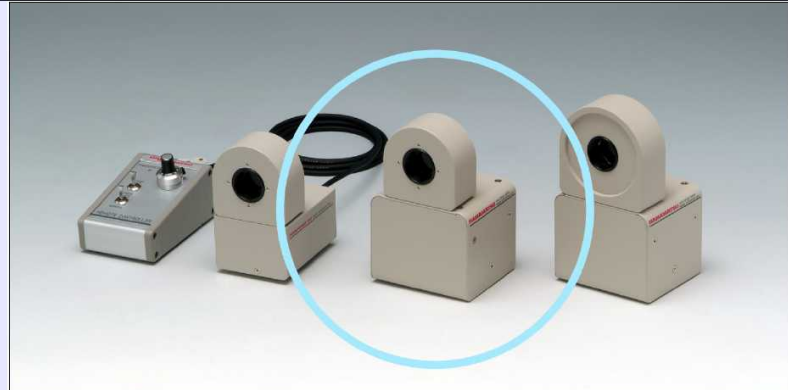


■ Afterpulsing AP (trapping of the electrons during discharge and delayed release)-fig.

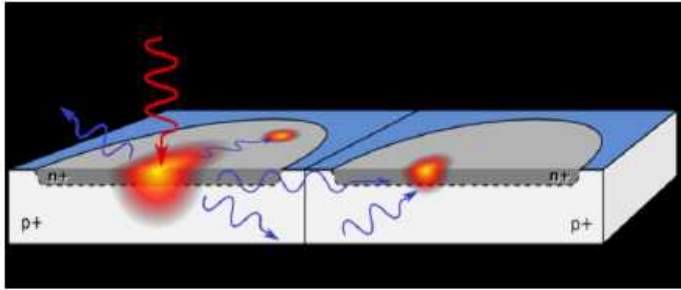
- ▶ AP is proportional to Gain -typically a few% \times Gain/ 10^{**6}
- ▶ AP increases the Dark Rate
- ▶ AP is high at small delays (< 1 mks)
 - ➔ need a single pixel recovery time of 1-5 mks
- ➔ Cooling does not help because the increase of trap lifetime

SiPM cross-talk

New measurements with high-speed gated image intensifier - 3ns gate
Hamamatsu C9546-05P47L



Main SiPM's parameters. Crosstalk

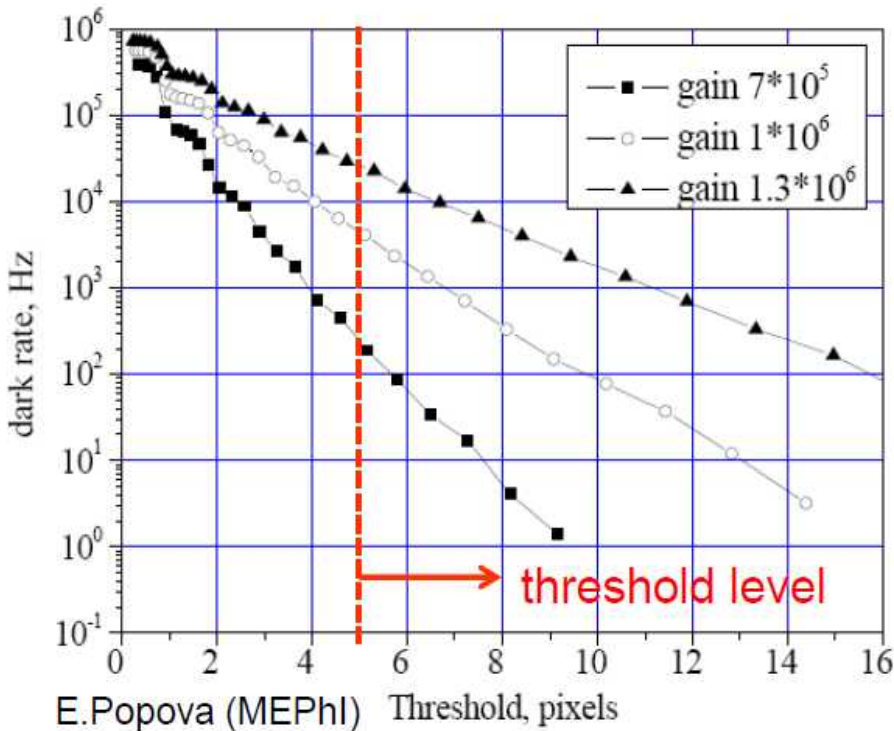


A p-n junction in breakdown emits photons in the visible range ($\sim 3 \times 10^{-5}$ per charge carrier with a wavelength less than $1 \mu\text{m}^*$)

If they reach a neighboring pixel additional breakdown can be caused

* A. Lacaita, et al., IEEE Trans. Electron Devices ED-40 (1993) 577

ron
Hole



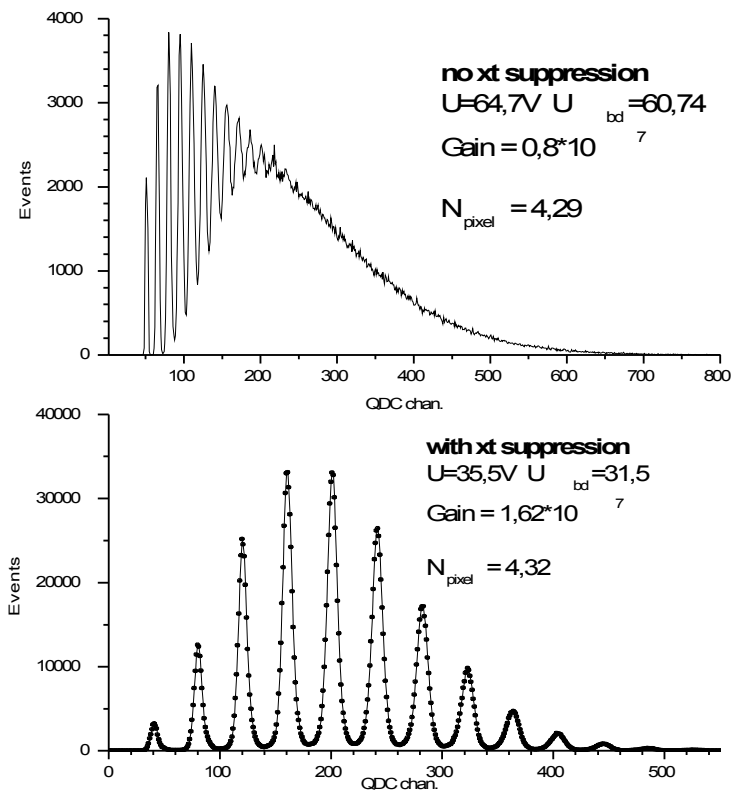
Optical crosstalk

- responsible for the high rate at thresholds > 1.5 p.e.
- Increases with overvoltage (or gain)
- Decrease effective dynamic range

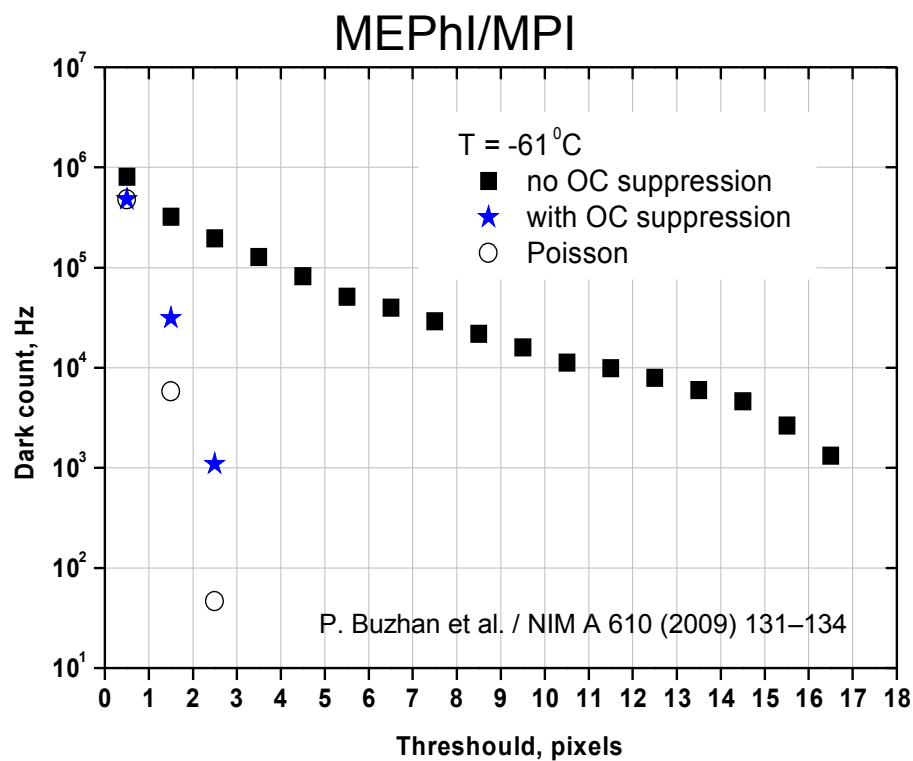
Limit to the SiPM sensitivity
Influence on acquisition rate & electronics design

Main SiPM's parameters. Crosstalk

Xt and light signal



Xt and dark rate



(IMAGING2010 Stockholm, Sweden June 8 – 11, 2010

B.Dolgoshein “Silicon Photomultiplier”)

Main protection from crosstalk – optical trenches between the SiPM pixels
 But only trenches are not enough!

Main SiPM's parameters. Crosstalk

Crosstalk from light spectra

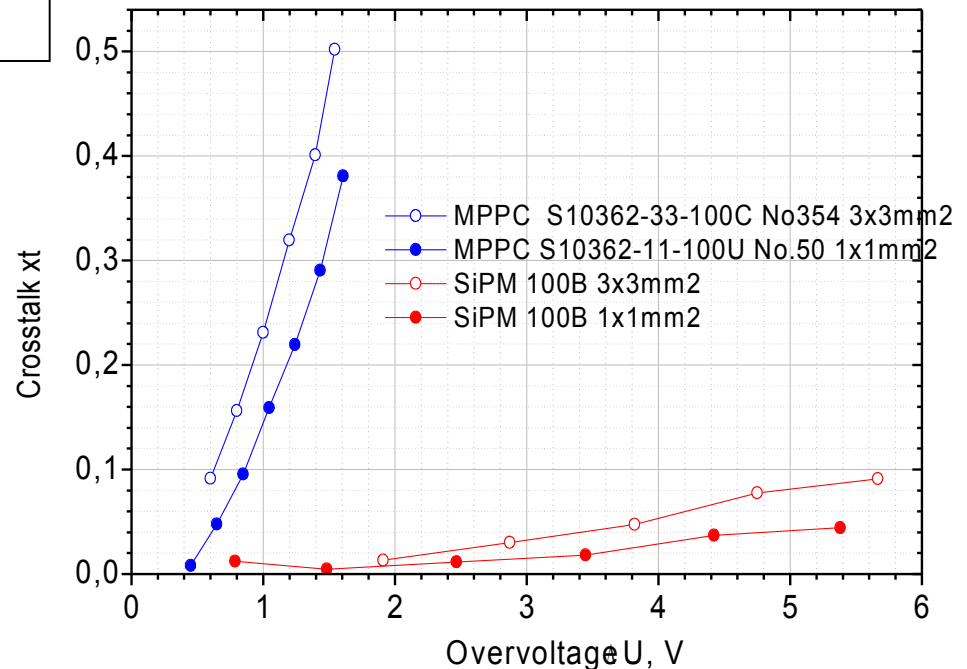
- V.Balagura, et al."Study of Scintillator Strip with Wavelength Shifting Fiber and Silicon Photomultiplier." NIM A564 (2006) 590-596
- S.Vinogradov et al."Probability distribution and noise factor of solid state photomultiplier signals with cross-talk and afterpulsing ". Nuclear Science Symposium Conference Record (NSS/MIC), 2009 IEEE

Crosstalk for latest MEPhi/MPI SiPM produced in cooperation with Excelitas and MPPC

100 micron pixel size,
geometrical efficiency 80%

$Xt = N_{>1.5} / N_{>0.5}$ crosstalk from dark rate

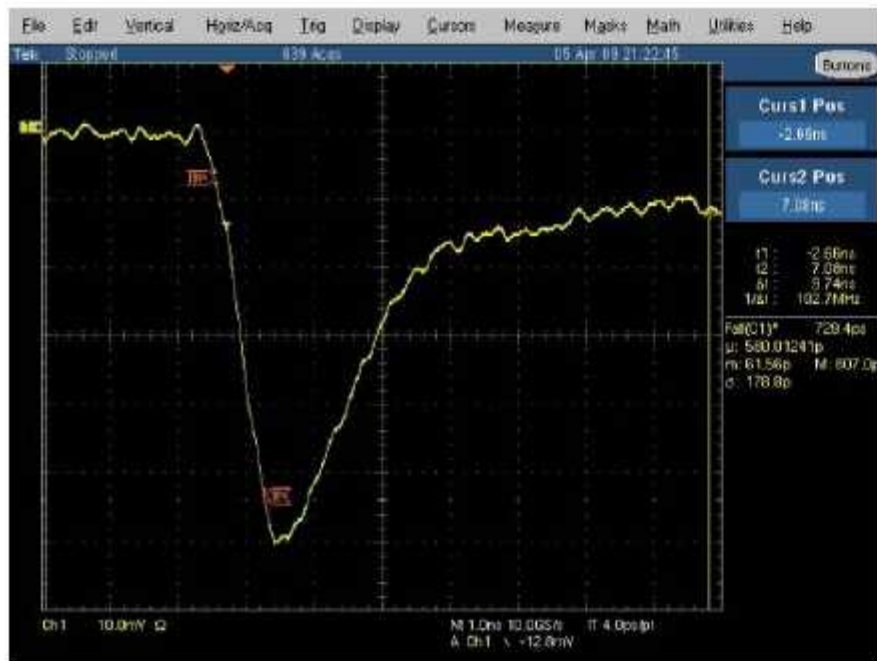
P.Eckert, et al."Characterisation studies of silicon photomultipliers." NIM A620 (2009), 217-226



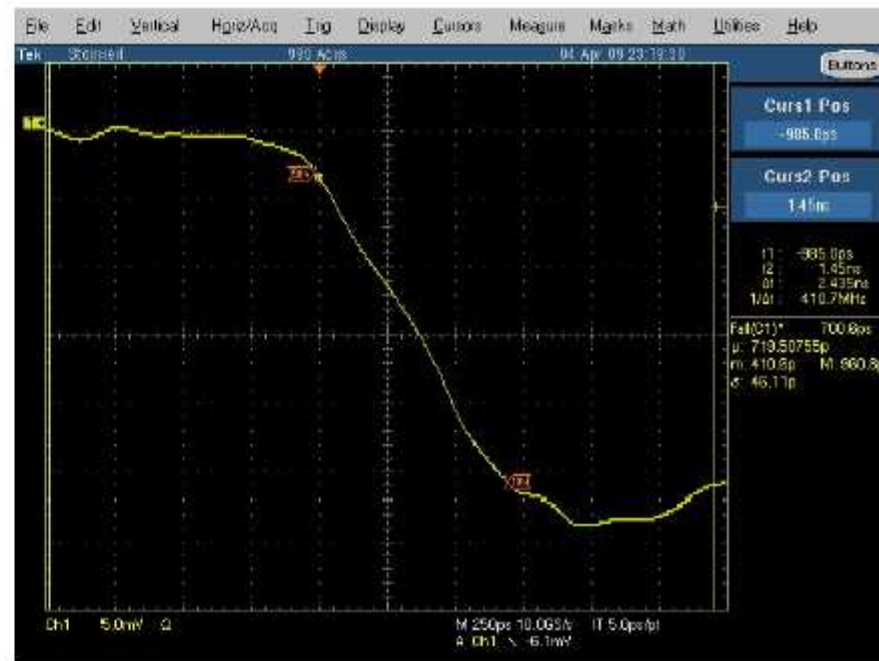
6th NDIP 2011 E. Popova et al.
"Large area UV SiPMs with extremely low cross-talk"

Signal rise time

CPTA/Photonique 1 mm² SSPM response to a 35 psec FWHM laser pulse ($\lambda=635$ nm)



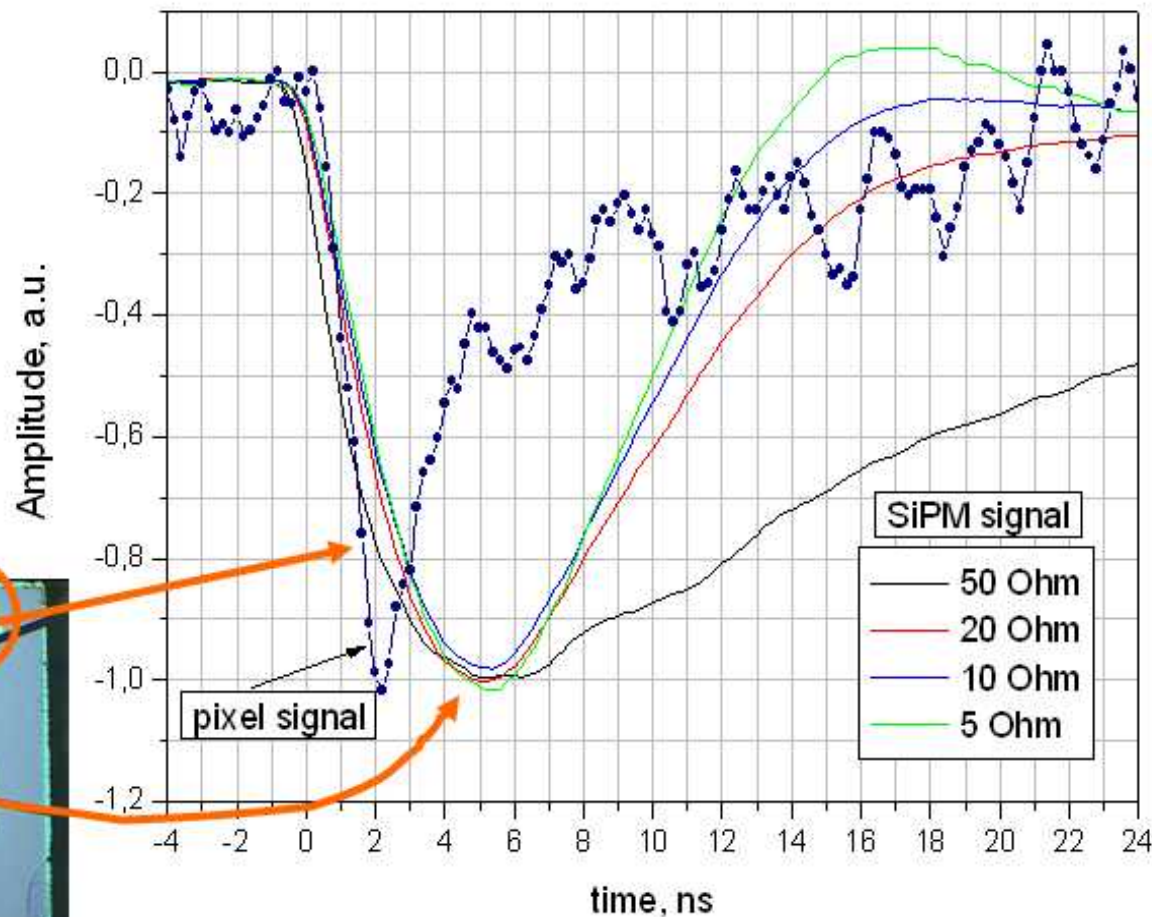
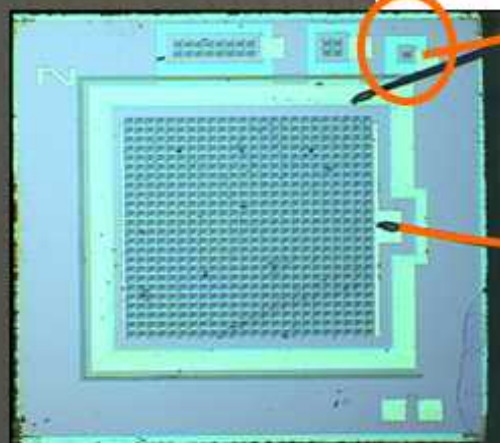
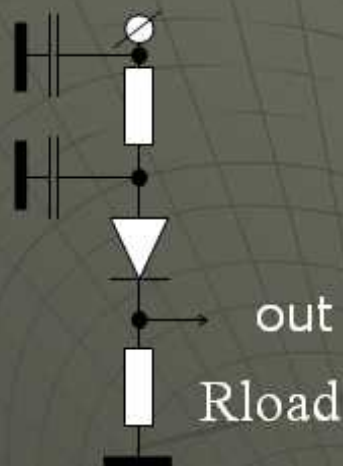
Zecotek 3x3 mm² MAPD response to a 35 psec FWHM laser pulse ($\lambda=635$ nm)



~700 psec rise time was measured (limited by circuitry)

5x5 mm² SiPM signal for different Rload

Connection scheme



Low input resistivity electronics is needed for fast sipm signal readout

VI Int. Workshop LIGHT 2007
Elena Popova Cooled SiPM
matrixes module

Cooled SiPM matrixes module for astropartical applications

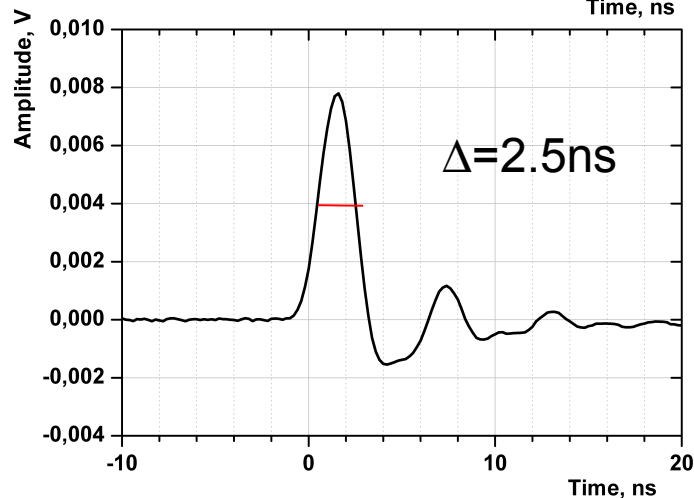
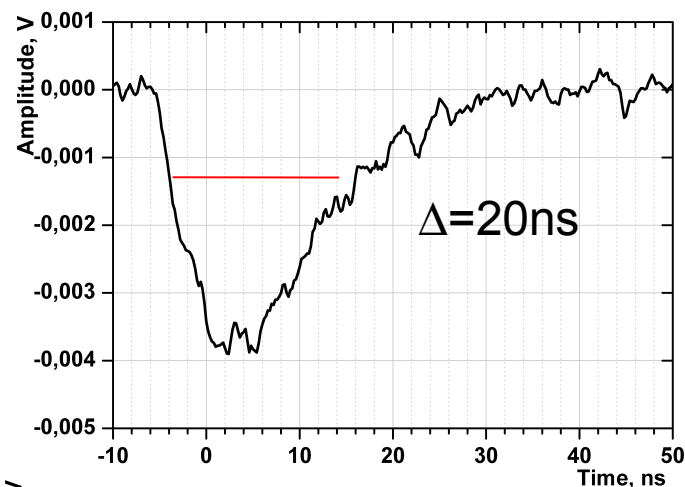
P. Buzhan et al. / NIM A 610 (2009) 131–134



Cooled module with 4 SiPMs 5x5mm²



SiPM 5x5mm² signals

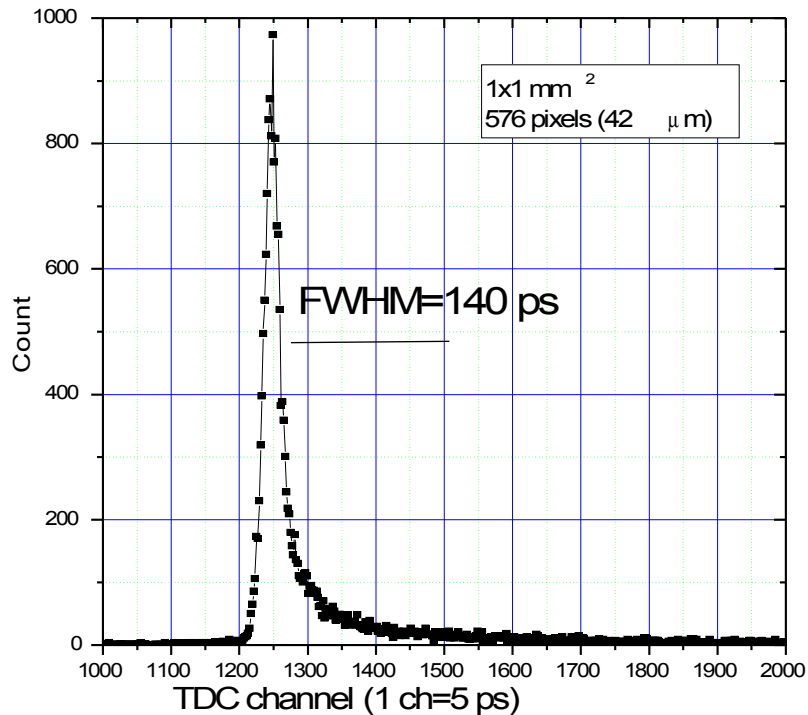


Main SiPM's parameters. Intrinsic jitter.

Laser in single photon mode

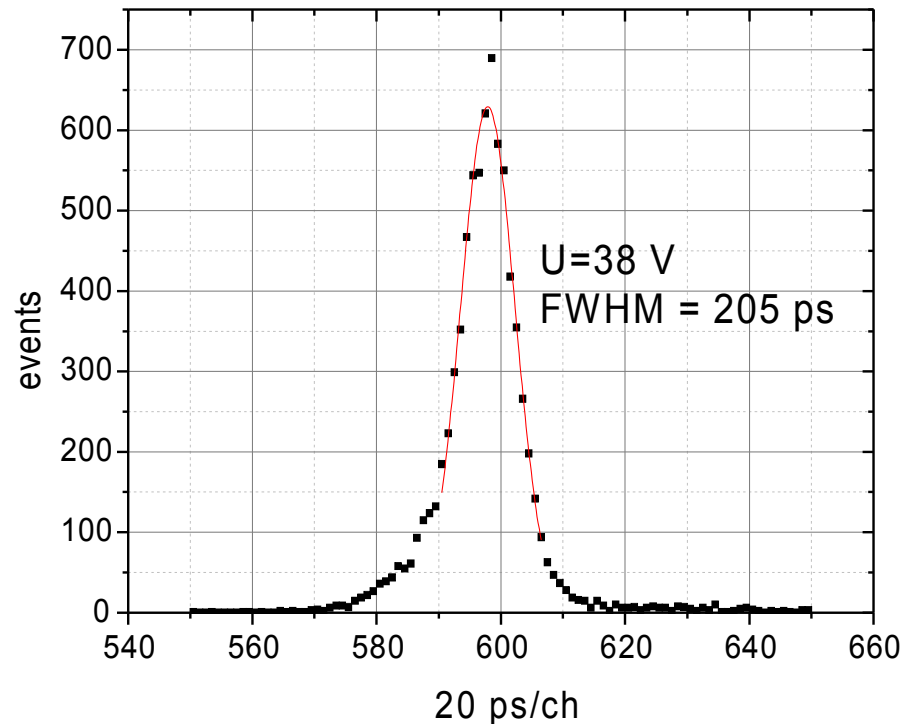
1x1mm²

Room temperature



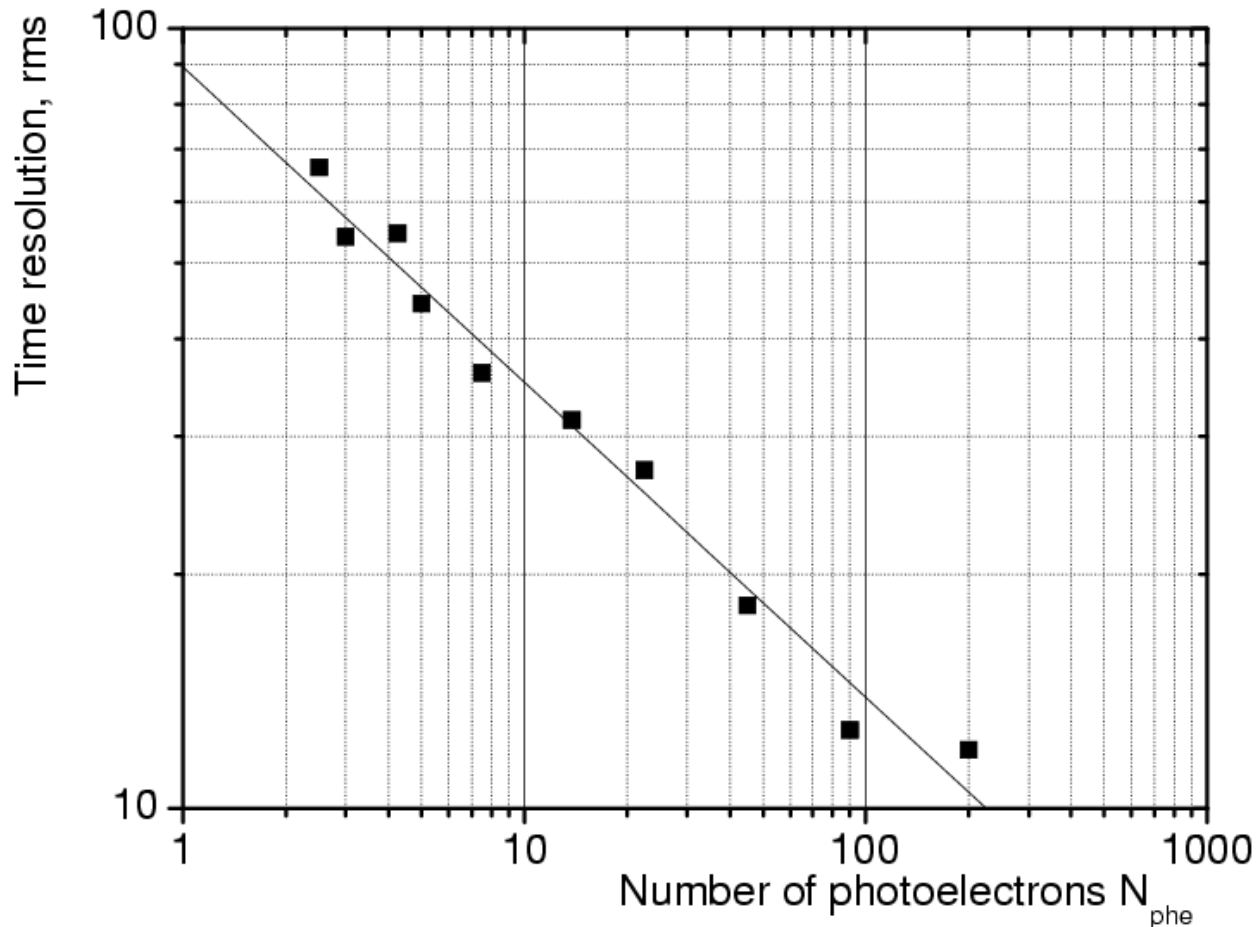
3x3mm²

Temperature -40C



35ps FWHM timing resolution was measured with 100μm SPAD using single photons
A.Gulinatti, P.Maccagnani, I.Rech, M.Ghioni and S.Cova

Main SiPM's parameters. Jitter vs light intensity.



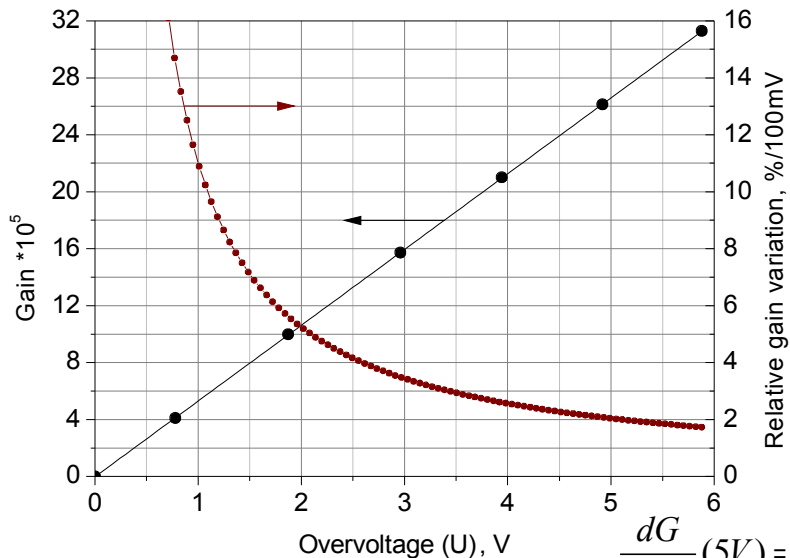
$$\sigma \sim \frac{1}{\sqrt{N_{phe}}}$$

ADVANCED TECHNOLOGY & PARTICLE PHYSICS Proceedings of the 7th International Conference on ICATPP-7
Villa, Olmo, Como, Italy, 15 - 19 October 2001

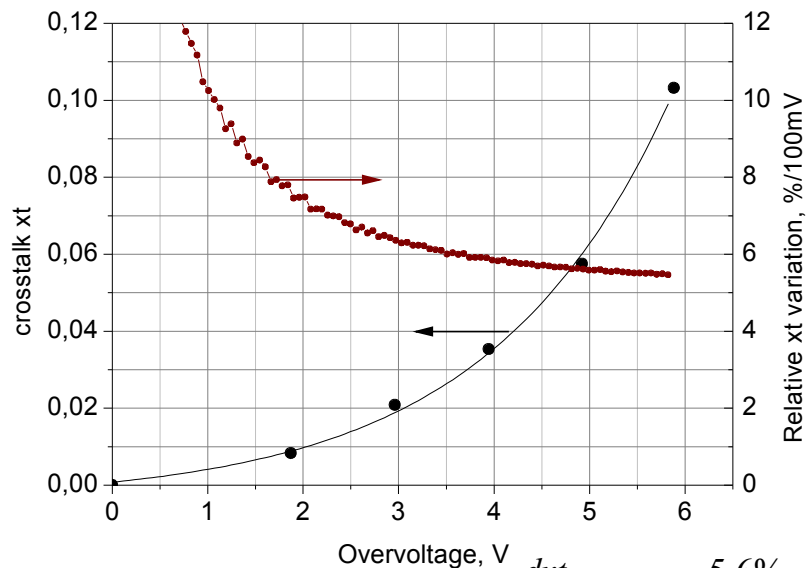
B.Dolgoshein et al. "THE ADVANCED STUDY OF SILICON PHOTOMULTIPLIER"

Voltage stability SiPM 100B for 5V (15%) overvoltage

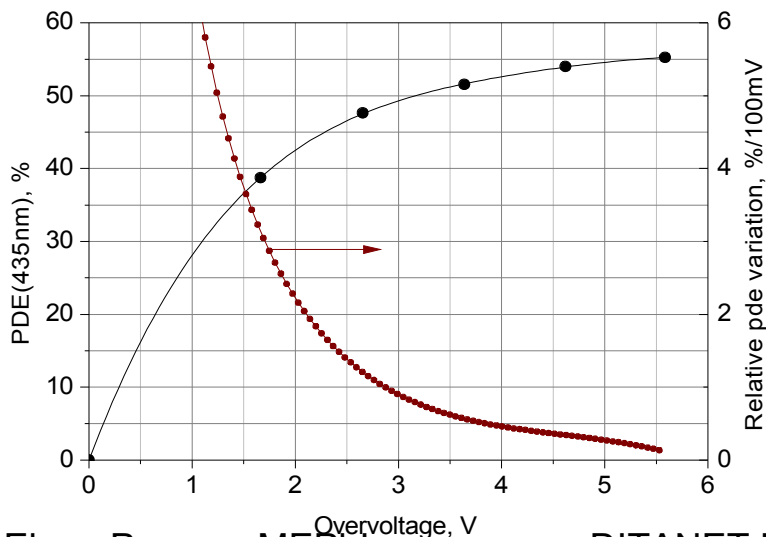
latest MEPhi/MPI SiPM produced in cooperation with Excelitas



$$\frac{dG}{GdU}(5V) = \frac{2.0\%}{100mV}$$



$$\frac{dxt}{xt dU}(5V) = \frac{5.6\%}{100mV}$$



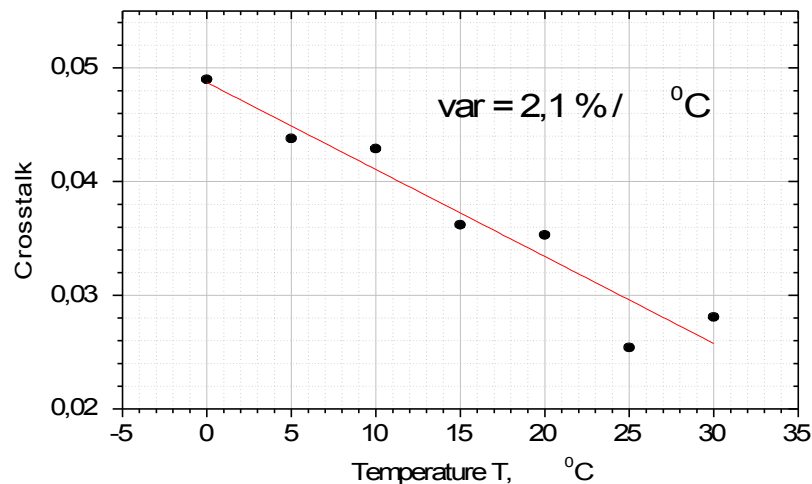
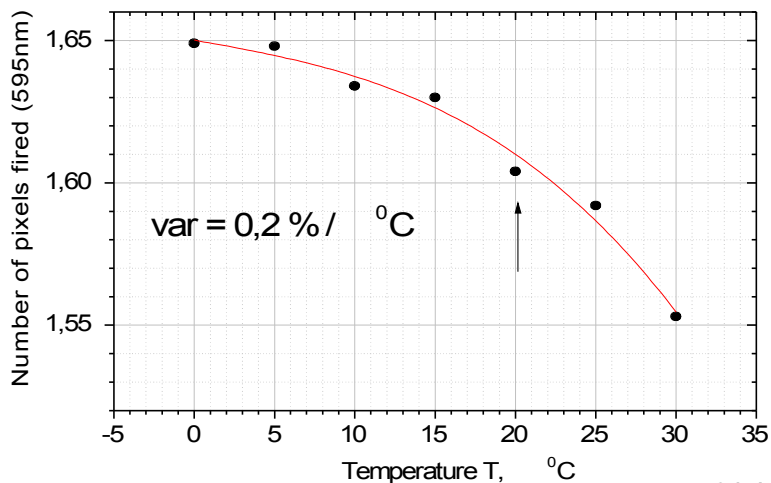
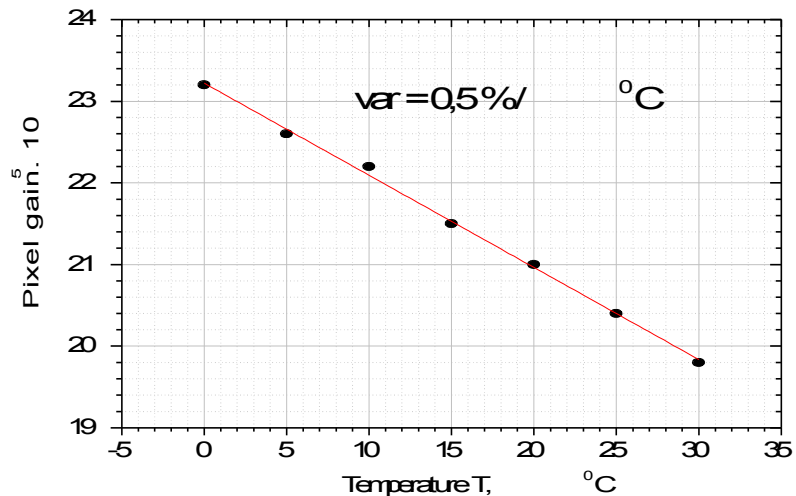
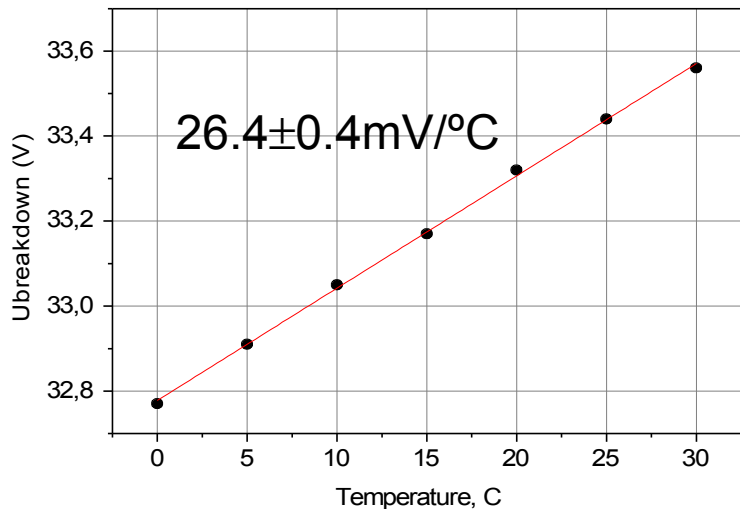
$$\frac{d\varepsilon}{\varepsilon dU}(5V) = \frac{0.25\%}{100mV}$$

6th NDIP 2011 E. Popova et al.
"Large area UV SiPMs with extremely low cross-talk"

Temperature stability SiPM 100B

latest MEPhi/MPI SiPM produced in cooperation with Excelitas

$\Delta V=4V$ (12%) overvoltage for $T=20^{\circ}\text{C}$



6th NDIP 2011 E. Popova et al.

"Large area UV SiPMs with extremely low cross-talk"

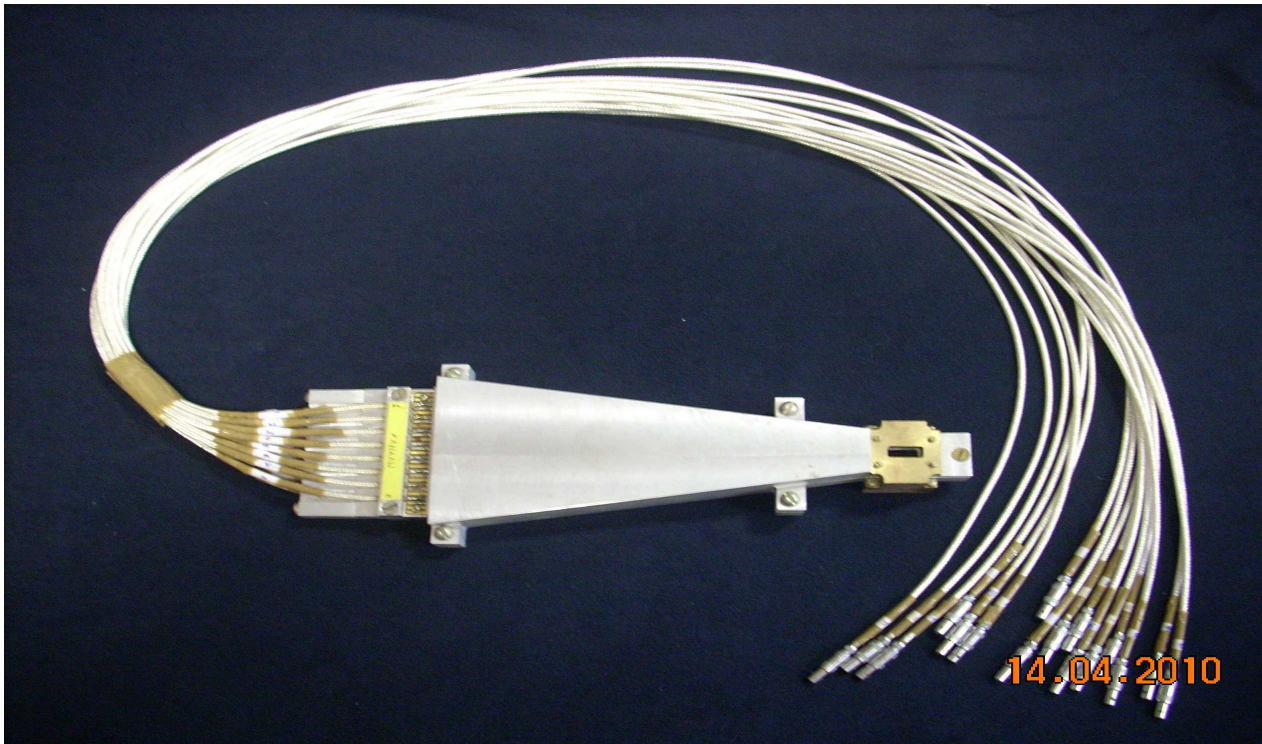
SiPM applications

16 channels (SiPMs) tracker on scintillating fibers

1x1mm² SiPMs

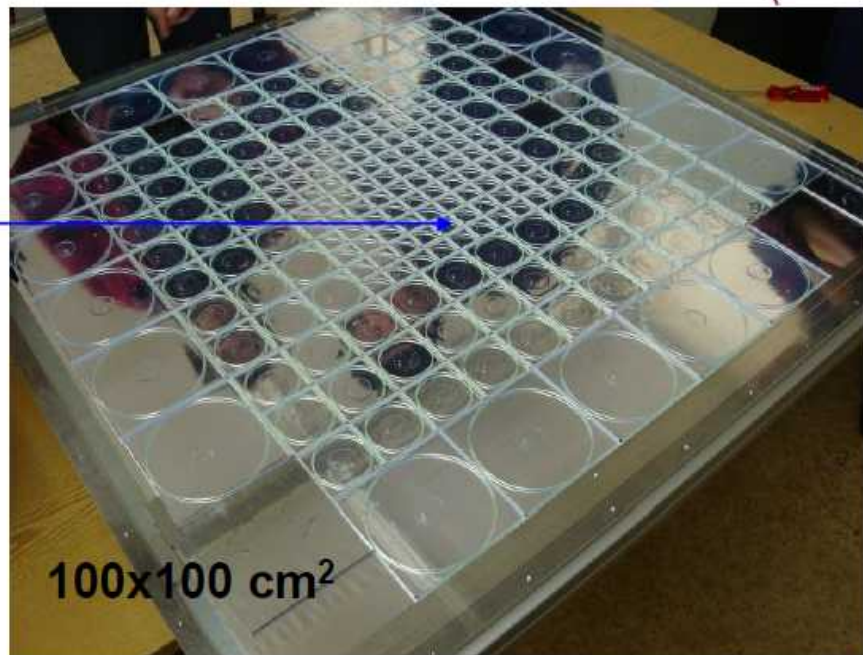
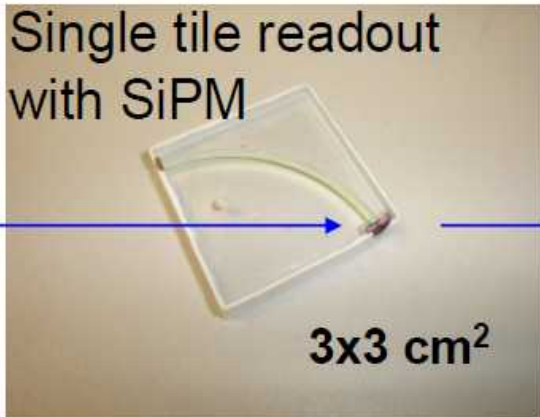
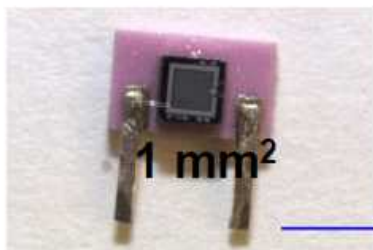
576 pixels

10% light detection efficiency for green light



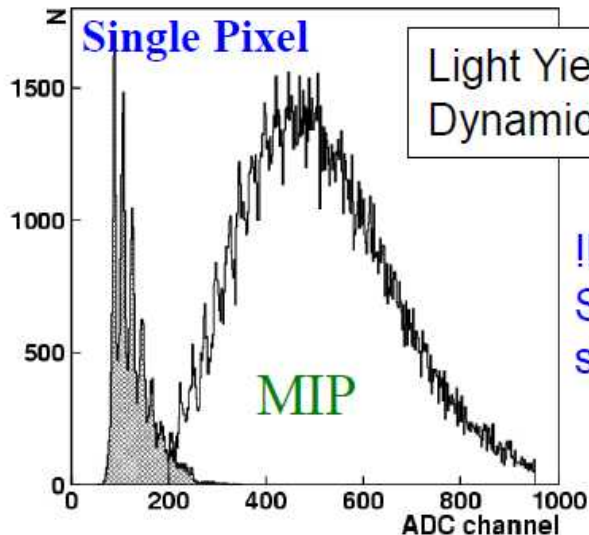
8th Workshop on Electronics for LHC Experiments, Colmar, France, 9 - 13 Sep 2002, pp.380-383
B.Dolgoshein et al."Scintillation fiber detector of relativistic particles".

A crucial technology improvement to calorimetry



Si-based = insensitive to magnetic field!

1x1m² prototype calorimeter with 8000 channels readout with SiPM (MePHI/Pulsar)



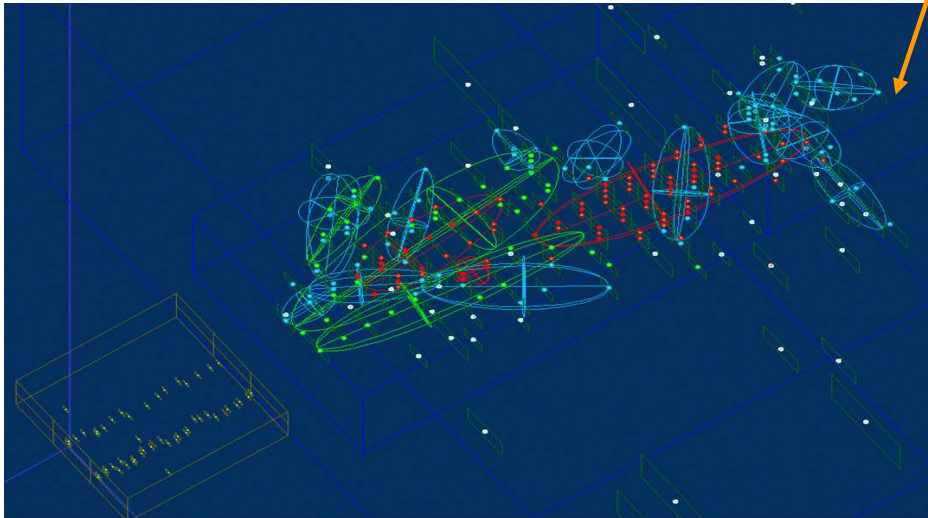
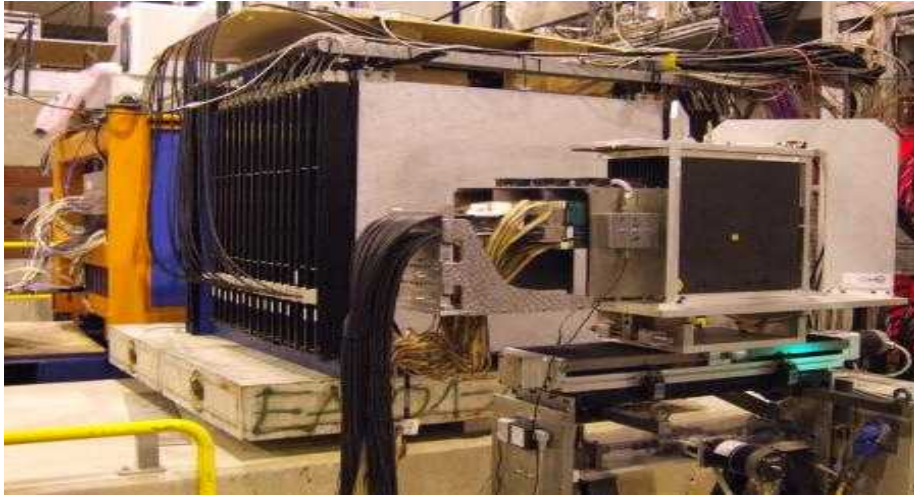
Light Yield = 15 pixels / MIP
Dynamic range ~ 100 MIPs

!! auto-calibration of SiPM gain from single-pixel spectra

Allows unprecedented high granularity

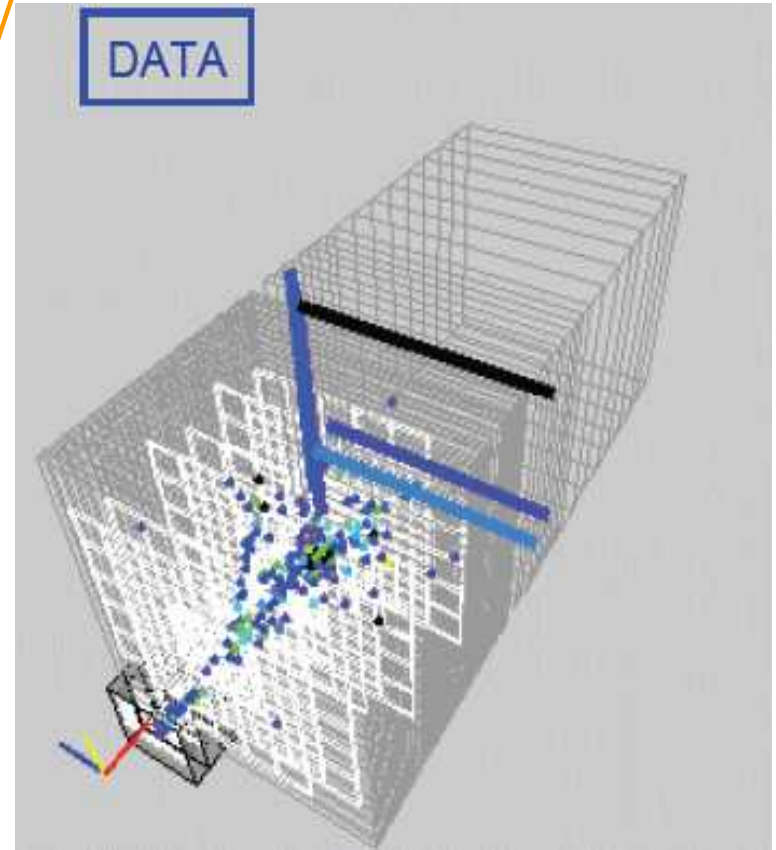
38 layers (~4.5 λ)
Scintillator – Steel sandwich structure (0.5:2cm)

Physical HCAL Prototype 2005-2007



Event reconstruction

Data monitor



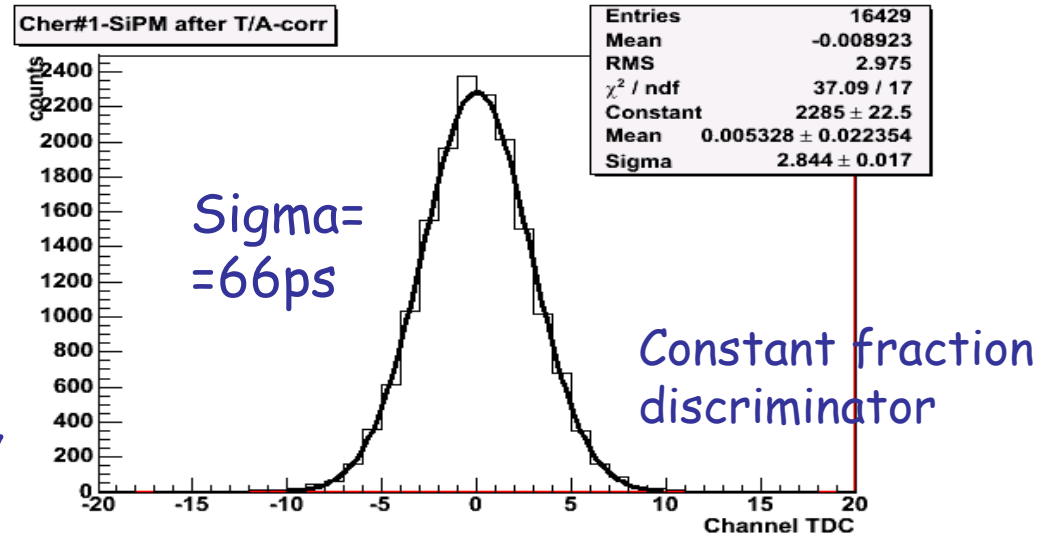
Prototype has been successfully tested at DESY, CERN and FNAL during several years

3x3 mm² SiPM application for TOF

➔ TOF for MIP(3GeV electron beam, DESY)



SiPM: MIP signal is appr. 100 mV w/o amplification



Timing resolution between :

PMT(FEU 187)+Cherenkov radiator
and SiPM 3x3mm²+BC418 3x3x40 mm³

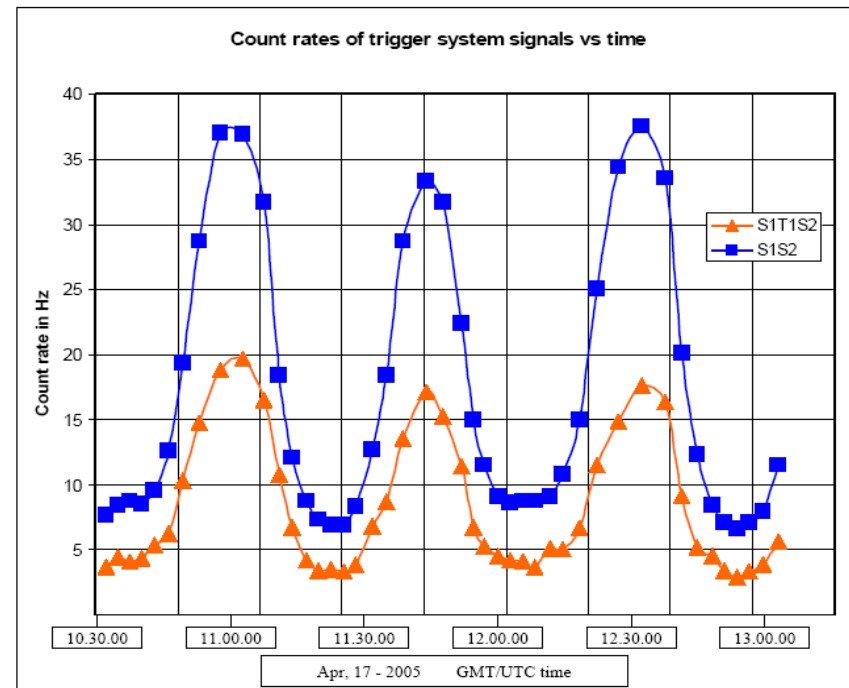
Results:

- sigma(PMT+Ch.rad)=48,5ps
- sigma(electronics) =32ps

➔ **Sigma(SiPM+BC418)=33ps**

SiPM's in space ! International Space Station: launched by 15th of April,2005

Space experiment "LAZIO"(MEPHI-INFN Collaboration)



Latitude particle flux dependence

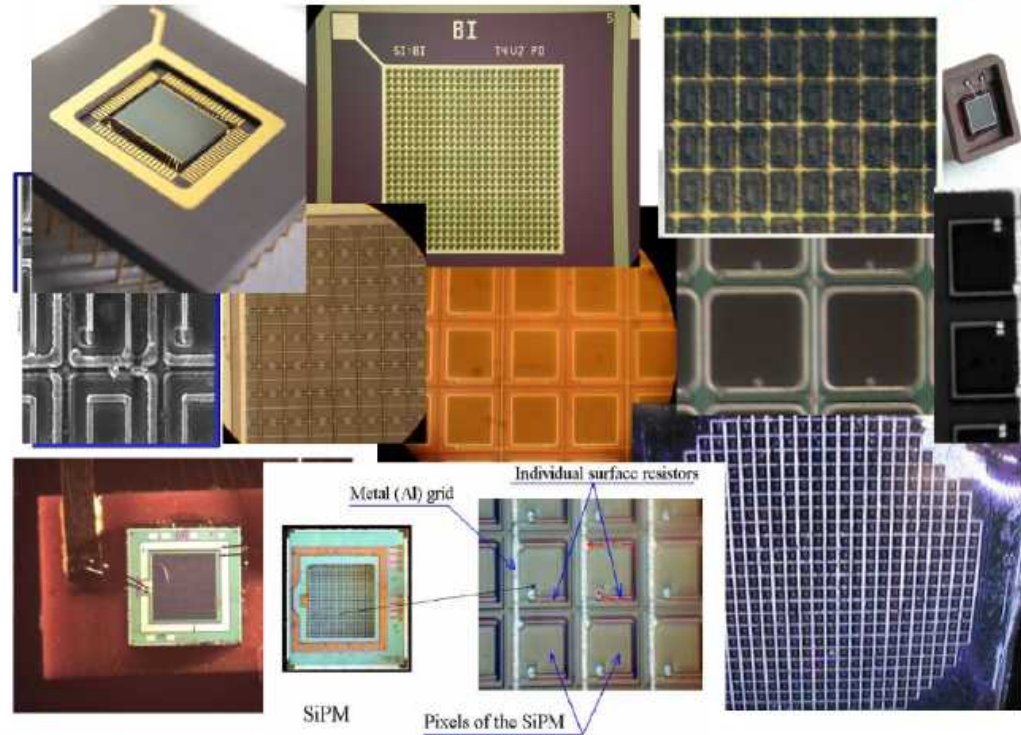
Scientific goal: The measurement of low energy particle fluxes and radiation monitoring by apparatus, including sci tile+WLS fiber+SiPM hodoscope system

Technological goal: test of SiPM's in space flight conditions

What is available



MEPhi/Pulsar (Moscow) - Dolgoshein
CPTA (Moscow) - Golovin
Zecotek(Singapore) - Sadygov
Amplification Technologies (Orlando, USA)
Hamamatsu Photonics (Hamamatsu, Japan)
SensL(Cork, Ireland)
AdvanSiD (former FBK-irst Trento, Italy)
STMicroelectronics (Italy)
KETEK (Munich)
RMD (Boston, USA)
ExcelitasTechnologies (former PerkinElmer)
MPI Semiconductor Laboratory (Munich)
Novel Device Laboratory (Beijing, China)
Philips (Netherlands)



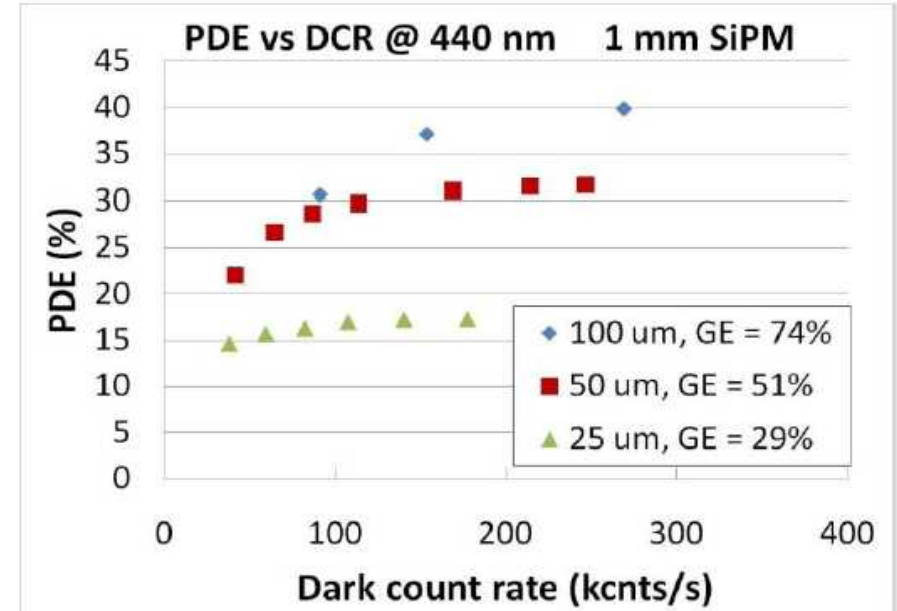
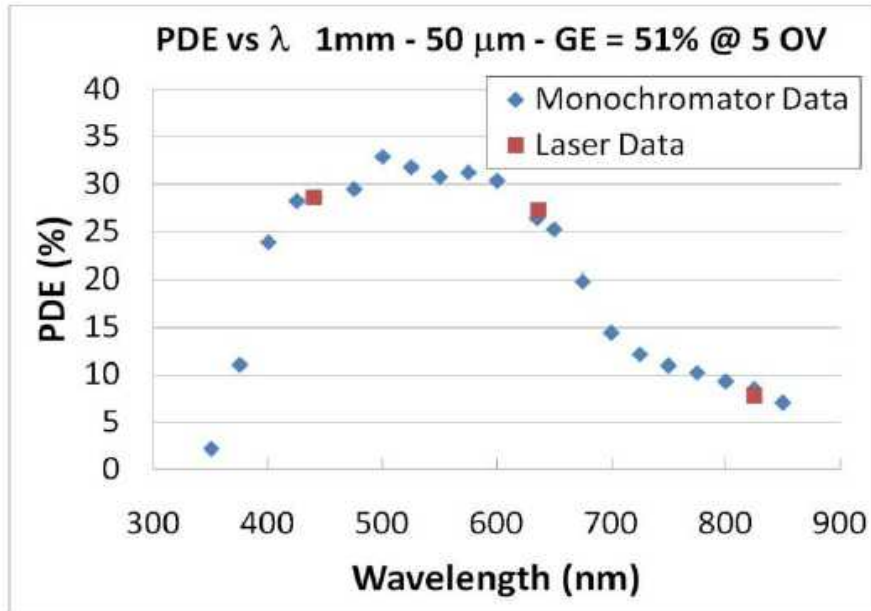
....

Every producer uses its own name for this type of device: MRS APD, MAPD, SiPM, SSPM, MPPC, SPM, DAPD, PPD, SiMPI , dSiPM...

Excelitas technologies



1st Generation SiPM, 2011 – highlights (3)



Broad responsivity spectrum

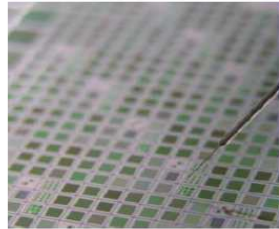
Low dark count even when PDE saturates

P. Bérard et al. "Characterization study of a new UV-SiPM with low dark count rate", 2011 NDIP Conference Record, NIMA

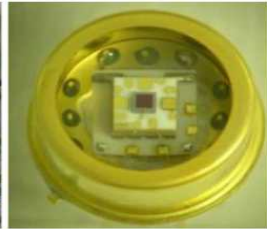
A Barlow, J Schilz, "SiPM developments", SiPM Matching Event, CERN, 16-17 Feb 2011

Excelitas technologies

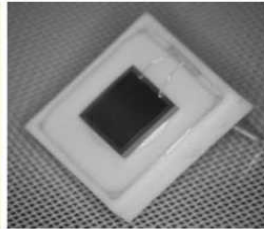
2nd Gen SiPM- Packaging Development



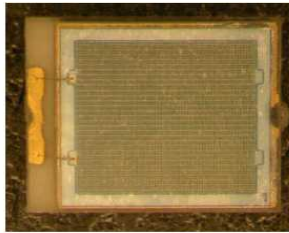
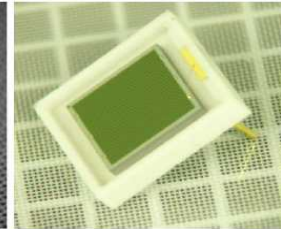
Wafer of chips



TO-can, cooler



Ceramic Header 3x3, 5x5



SMT package
(tile-able)

Packaging Development
progressing alongside,
1,3 and 5 mm chip sizes

Almost ready for market!

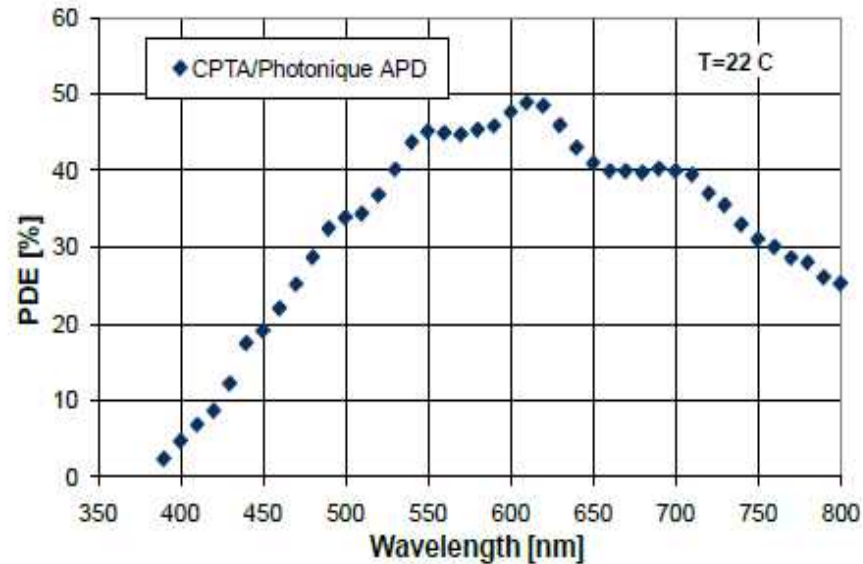
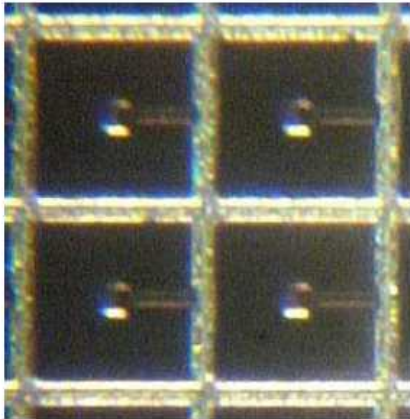
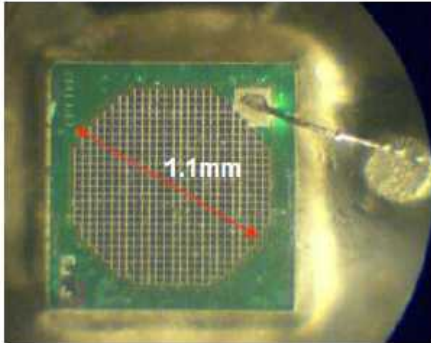
EXCELITAS
TECHNOLOGIES

20

No crosstalk protection yet but is going to implement
Goal – to have the lowest dark rate
Final product in early 2012

Addressing the needs of molecular imaging and high energy physics communities

CPTA(Golovin)/Photonique SSPM

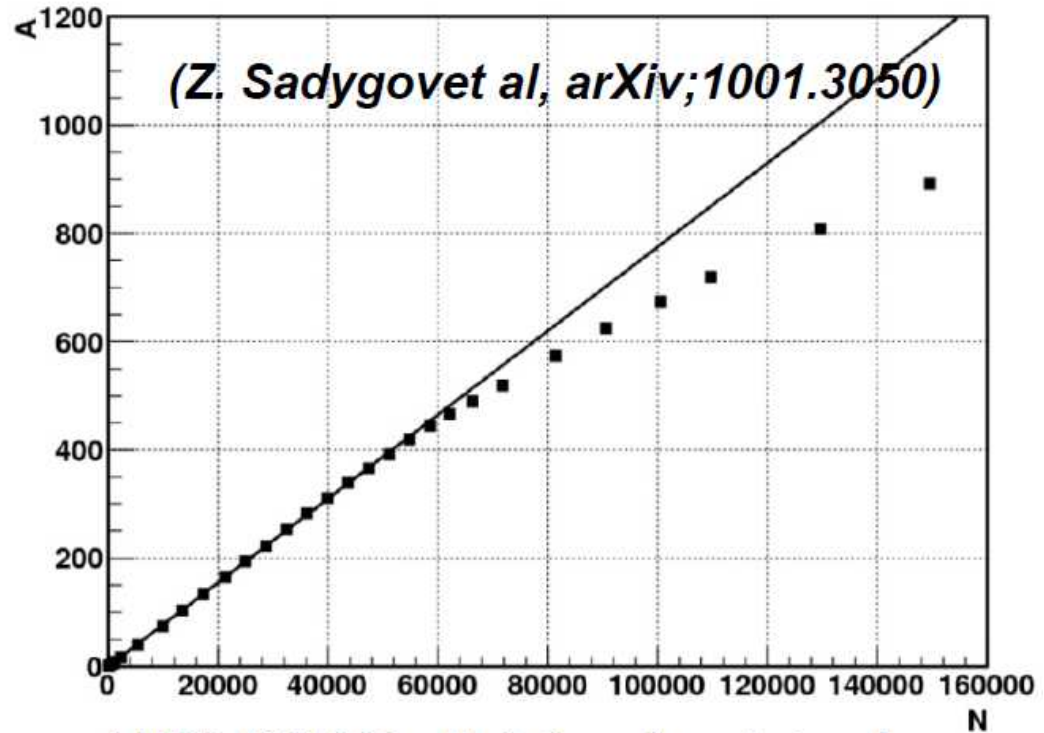
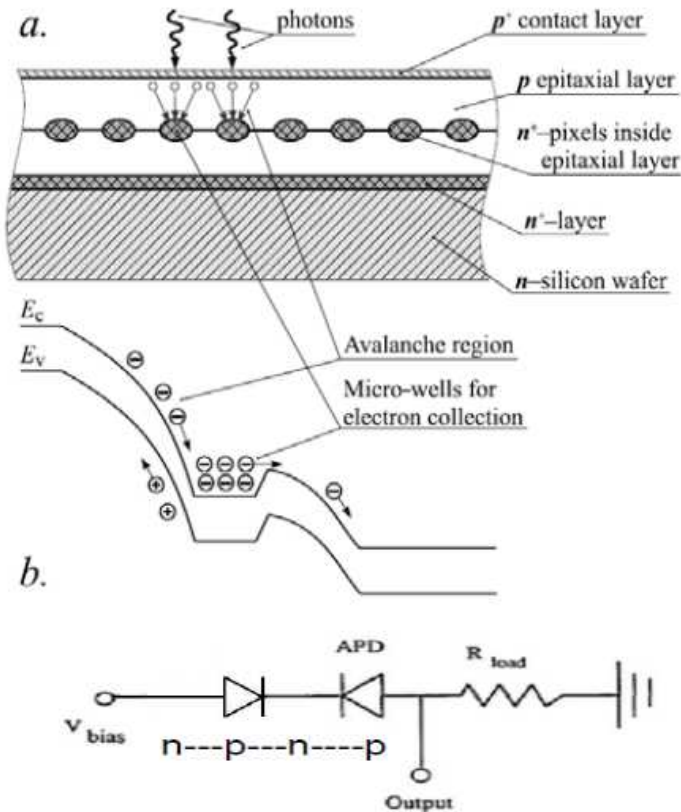
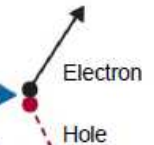


(Y. Musienko, PD-07, Kobe)

SiPMs with 60-80% geometric factor (for 50-100 μm cell pitch) were produced
High sensitivity in green-red region
With optical crosstalk suppression

High dynamic range → MAPD from Zecotek

Micro-well structure at 2-3 μm depth with multiplication regions located in front of the wells offer 10000–40000 cells/ mm^2 and up to 3x3 mm^2 in area were produced by Zecotek

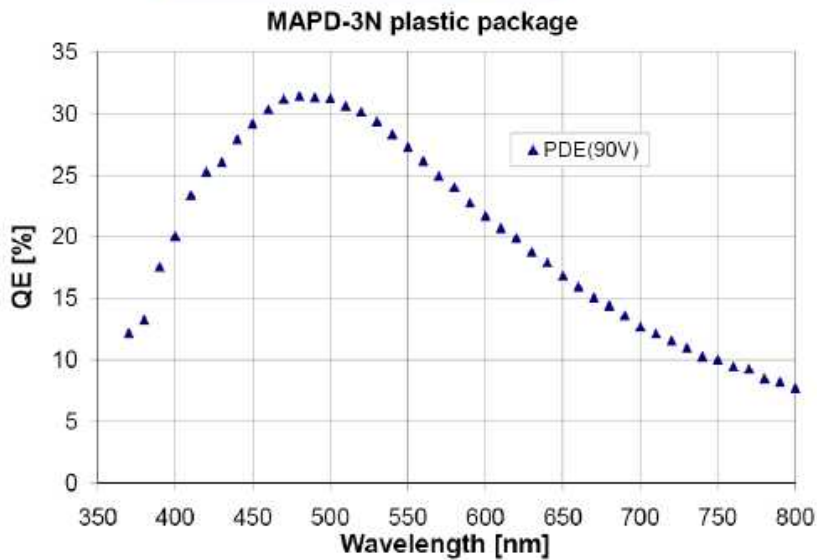


MAPD (135000 cells, 3x3 mm^2 area) signal amplitude A (in relative units) as function of a number of incident photons N

No quench resistors instead specially designed potential barriers are used to quench the avalanches.

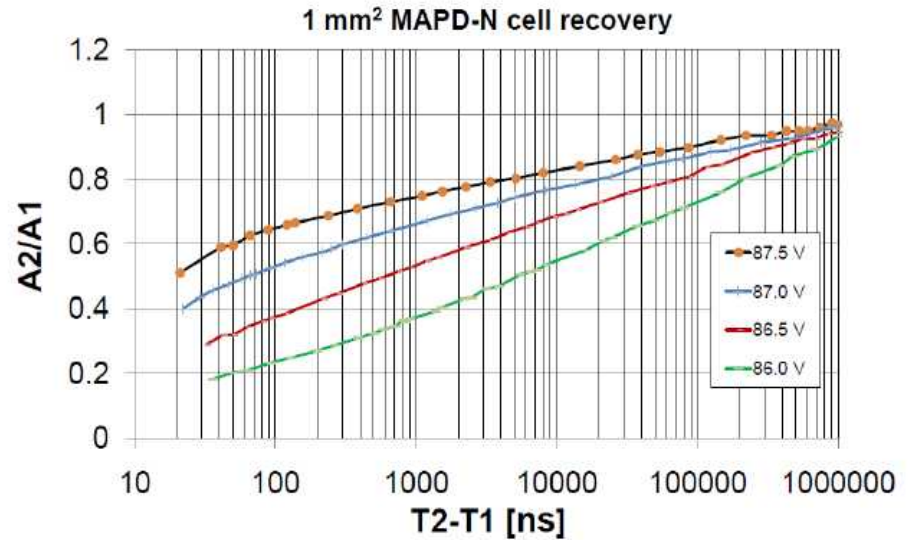
Zecotek

PDE vs. wavelength



MAPD cell recovery is not exponential

MAPD (3N type) cell recovery (measured using 2 LED technique)

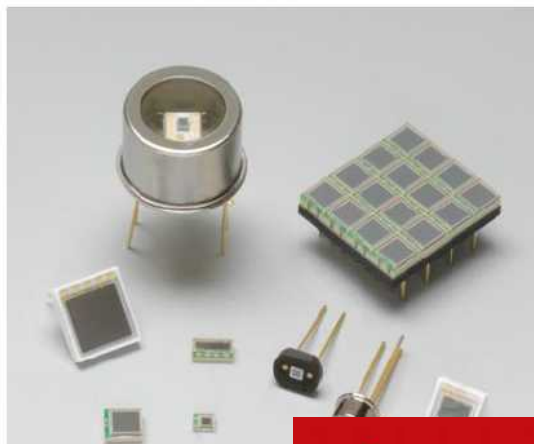


CERN, SiPM workshop, 16.02.2011

Y. Musienko (louri.Musienko@cern.ch)

Multi-Pixel Photon Counter (MPPC)

MPPC® is the solid state photon counter having Multi pixelated Geiger-mode APDs with self-quenching resistance.



Most widely used SiPM like devices

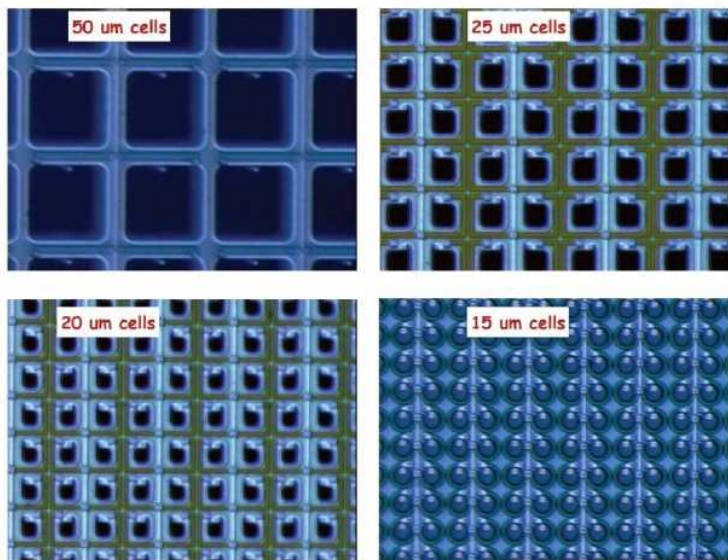
Large dynamic range

Multichannels for tracker

A lot of different modifications but

No optical crosstalk protection

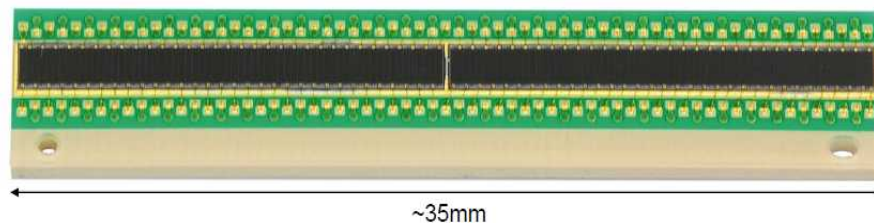
Custom-made MPPC example



ht © Hami

MPPC linear array 128ch - developed for fiber tracker

- 2 chips/assembly
- Gap between active area of chips : 250um (= 1ch)
- Buttable device (aimed gap : also 250um)
- Thin epoxy layer: minimize optical cross-talk

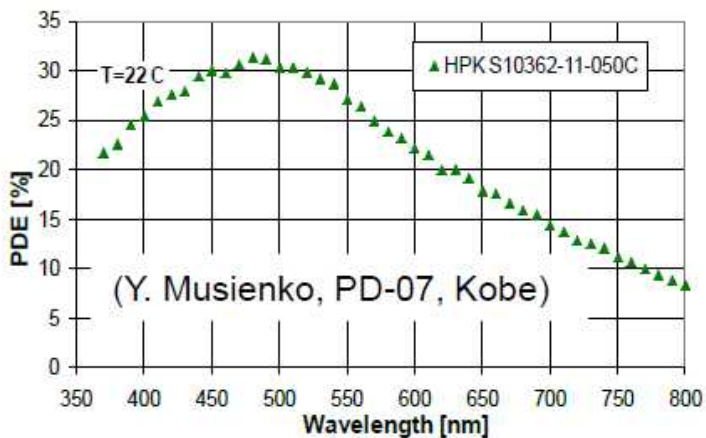


Elena Popova, MEPhI

DITANET I

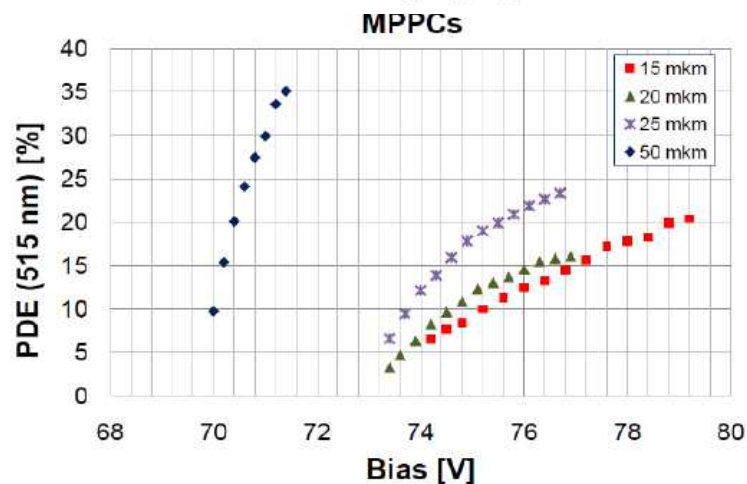
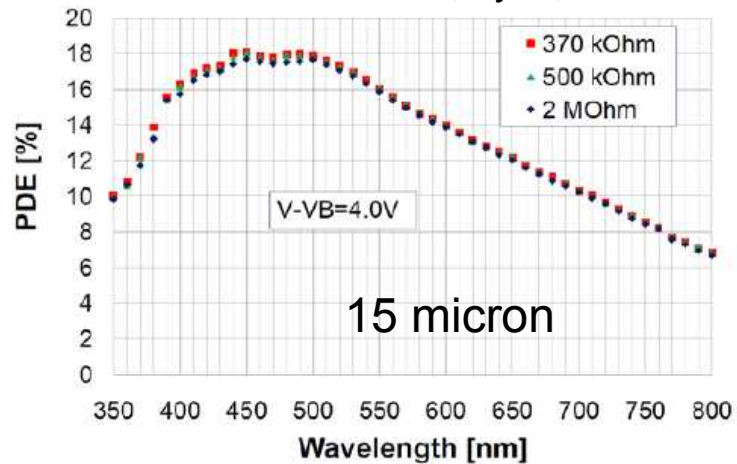
MPPC's PDE without crosstalk and afterpulsing

Hamamatsu MPPC (50 μm cell pitch)



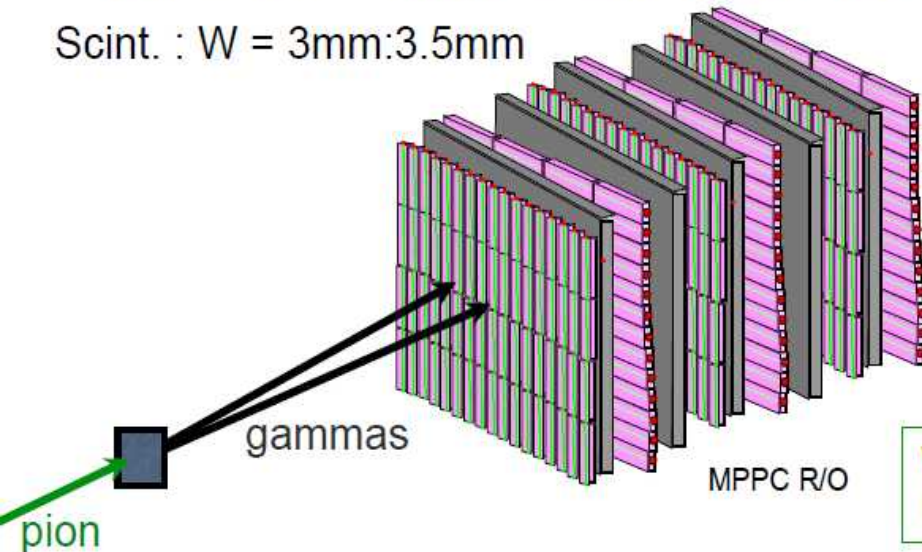
PDE is lower then specified by Hamamatsu

Y. Musienko *NDIP-2011, Lyon, 8.07.2011*



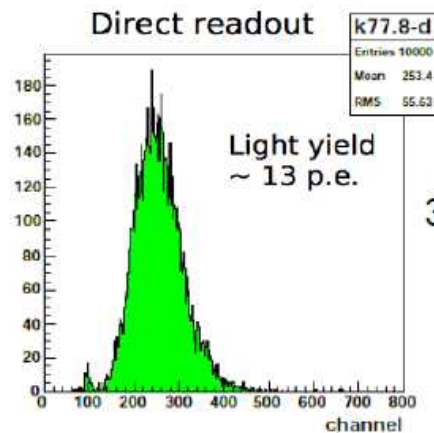
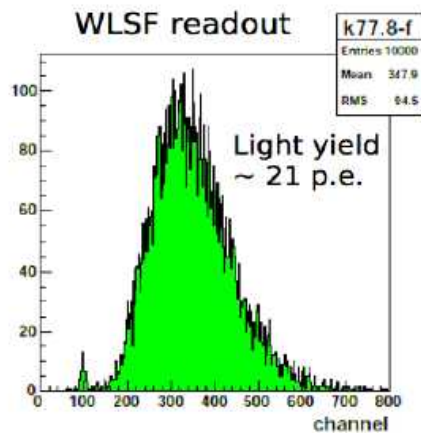
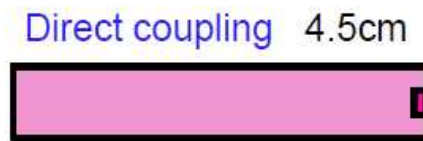
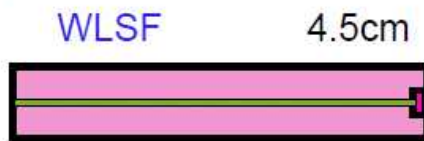
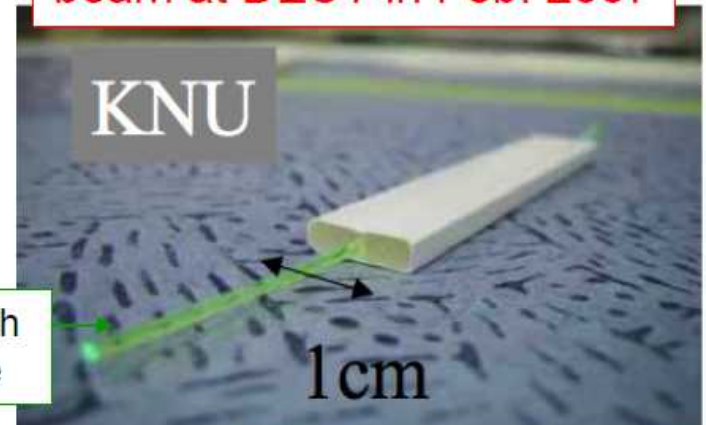
Scintillator – Tungsten sandwich structure

Scint. : W = 3mm:3.5mm

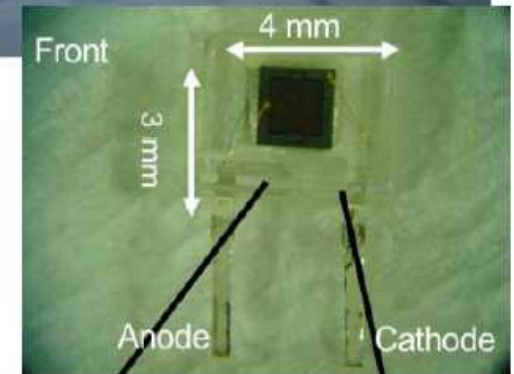


Electron
Hole
from T. Takeshita, Shinshu Uni., Japan

Fist prototype ready for test beam at DESY in Feb. 2007



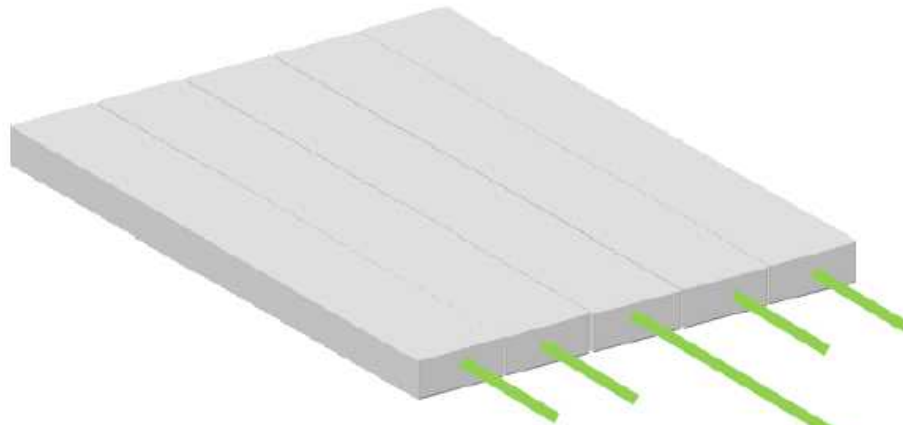
3M R.M.F.



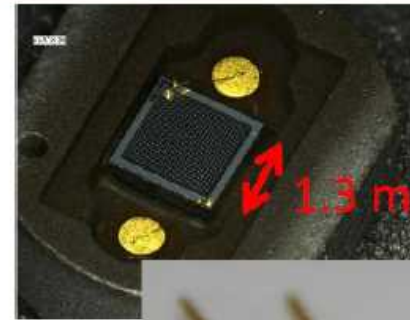
Multi-Pixel Photon Counter
from Hamamatsu

The design solution

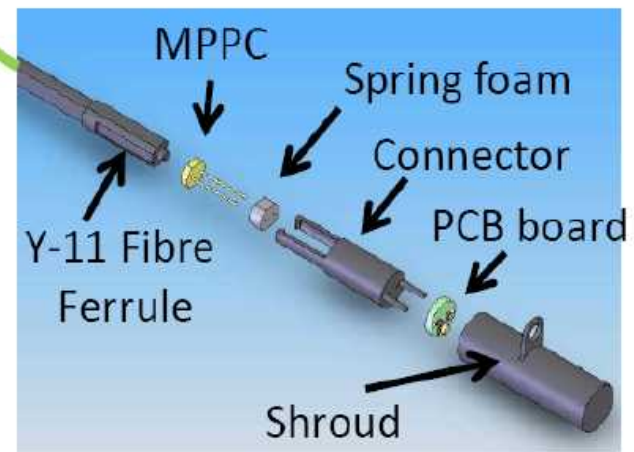
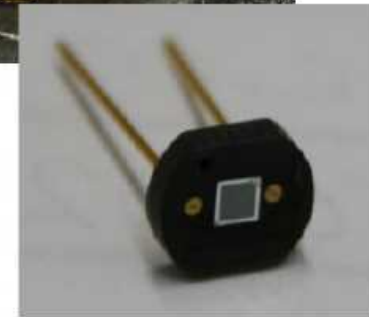
T2K experiment



- Basic element of the near detector scintillator subsystem (INGRID, POD, FGD, ECAL, SMRD)
 - Extruded scintillator bar with embedded Y-11 fibre read out by individual MPPC in coupler
 - **56000 channels in total**



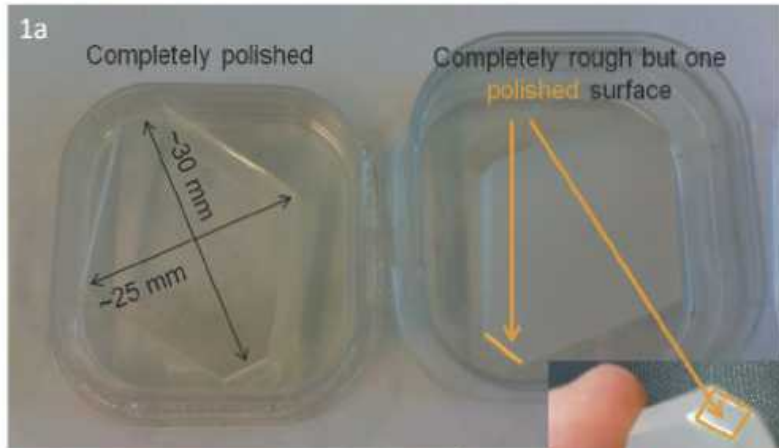
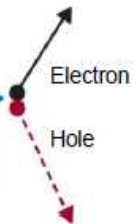
MPPC



Connectors for POD/ECAL/SMRD

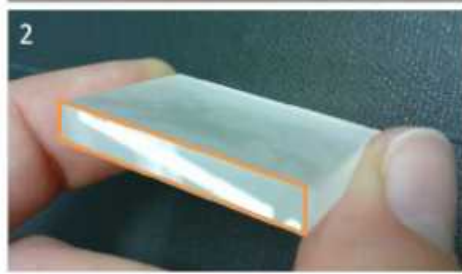
18

Cherenkov light r/o

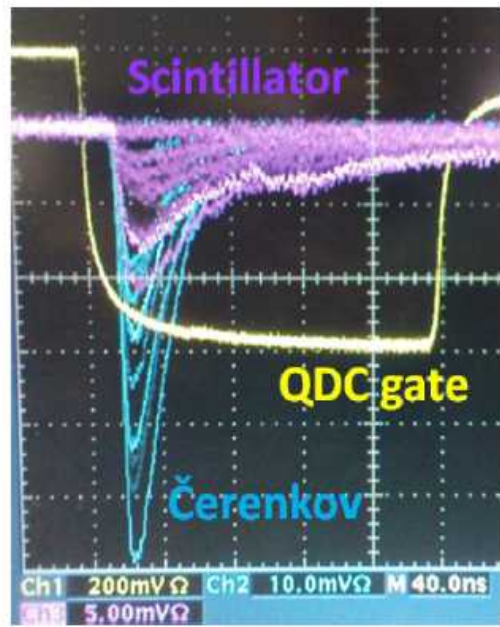


First test of Cherenkov light detection from Sapphire and lead glass tiles

S. Jungmann, diploma thesis, Heidelberg



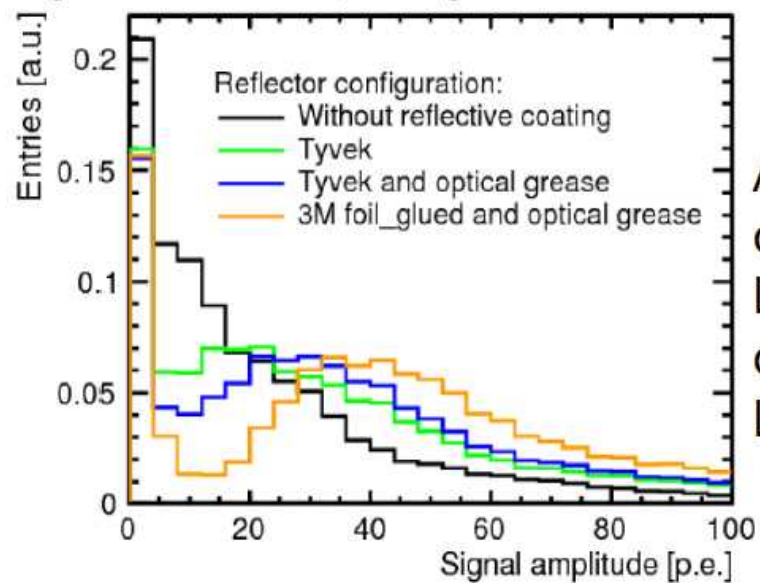
Tested at DESY TB with 3 GeV electrons



Coupled to 3x3 mm² MPPC, 50um pixel

Possible application in Dual readout calorimetry (CLIC?)

Signal of Cherenkov Tile, low range



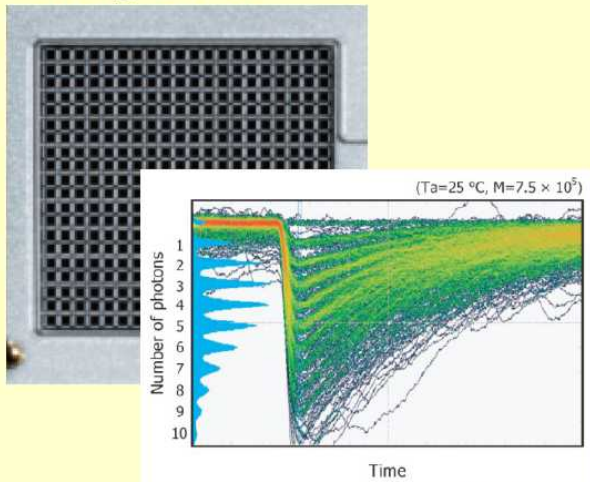
After optimization of coating and coupling LY sufficient for calorimeter application
LY uniformity under study

Philips

PHILIPS

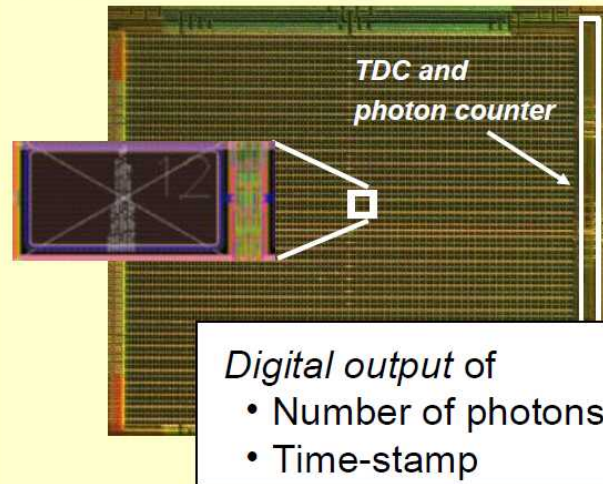
Digital SiPM – New Type of Silicon Photomultiplier

Analog SiPM



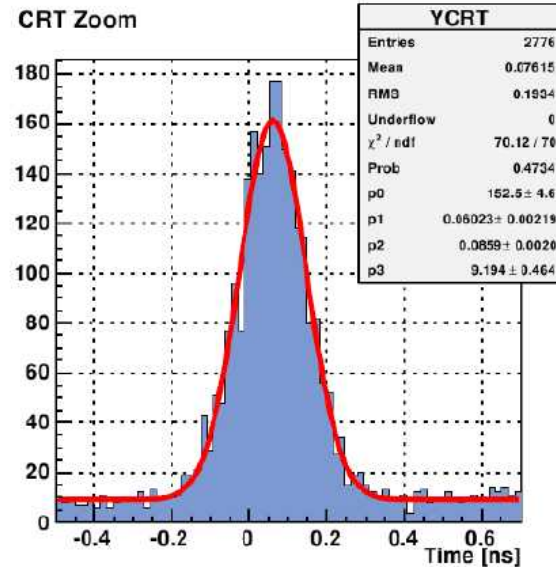
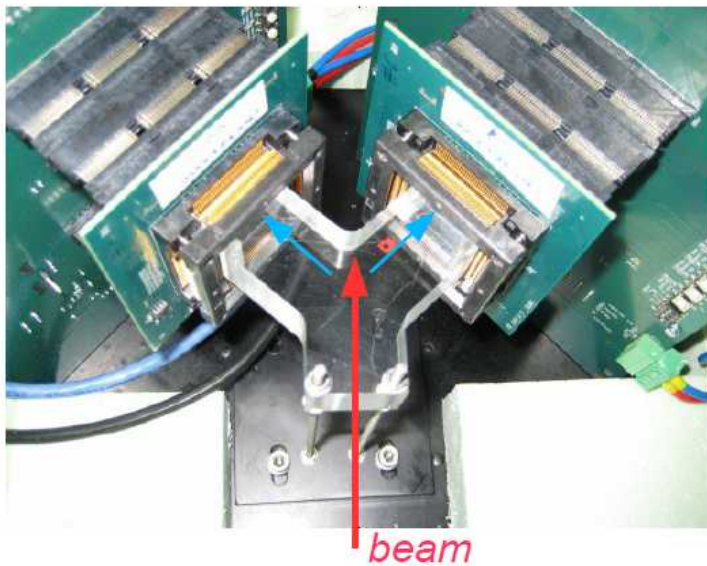
- Cells connected to common readout
- Analog sum of charge pulses
- Analog output signal

Digital SiPM



- Each diode is a digital switch
- Digital sum of detected photons
- Digital data output

DLD8K – Čerenkov Light Detection



- PMMA radiator coupled via air gap to two dSiPMs (DLD8K) in coincidence
- Box isolated and temperature-controlled with a TEC to 2 – 3°C
- Cooperation between Giessen University (Prof. Düren) and Philips DPC
- First measurements at CERN SPS: $\sigma = 60.7\text{ps}$

Nice amplitude and timing parameters of signal after post-processing but with slow readout

LIGHT 2011

17

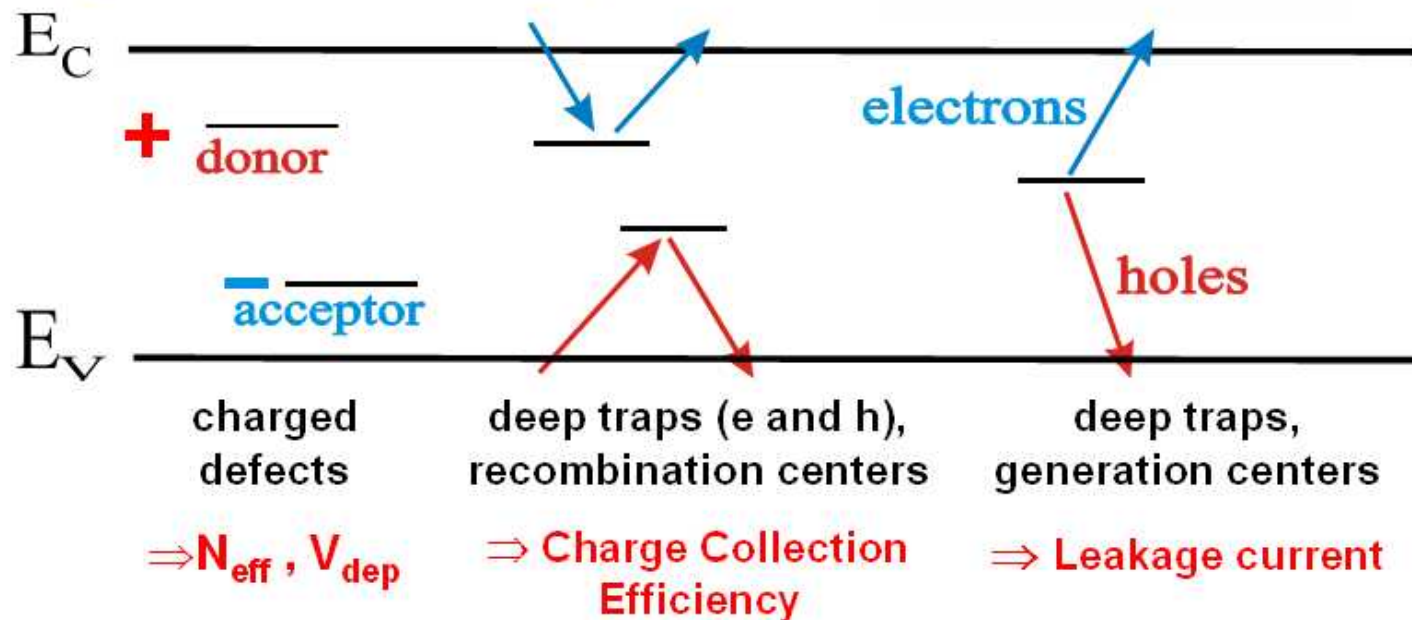
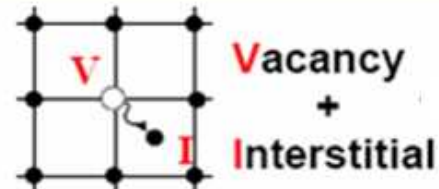
Radiation hardness?

Radiation Damage in Silicon

I. **Surface Damage** due to **Ionizing Energy Loss (IEL)**

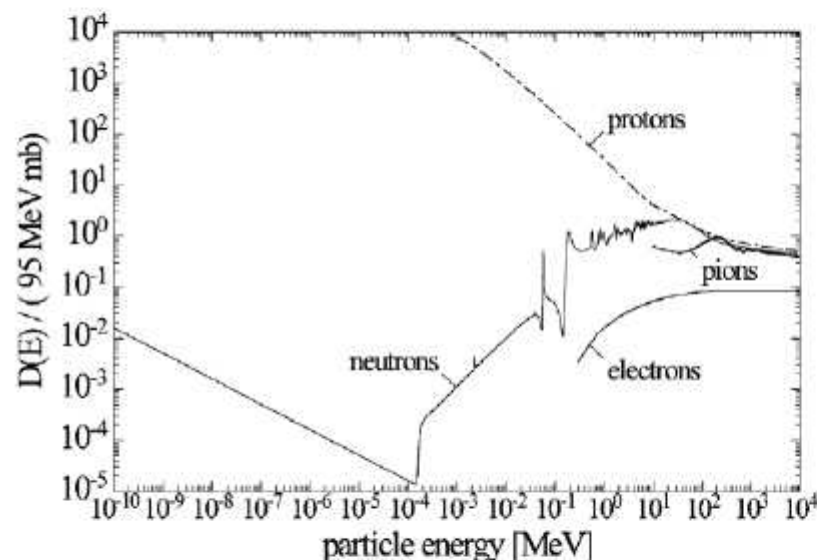
II. **Crystal (Bulk) damage** due to **Non-ionizing Energy Loss (NIEL)**

- defects in the crystal
- point defects and “cluster” defects
- energy levels in the band gap filled

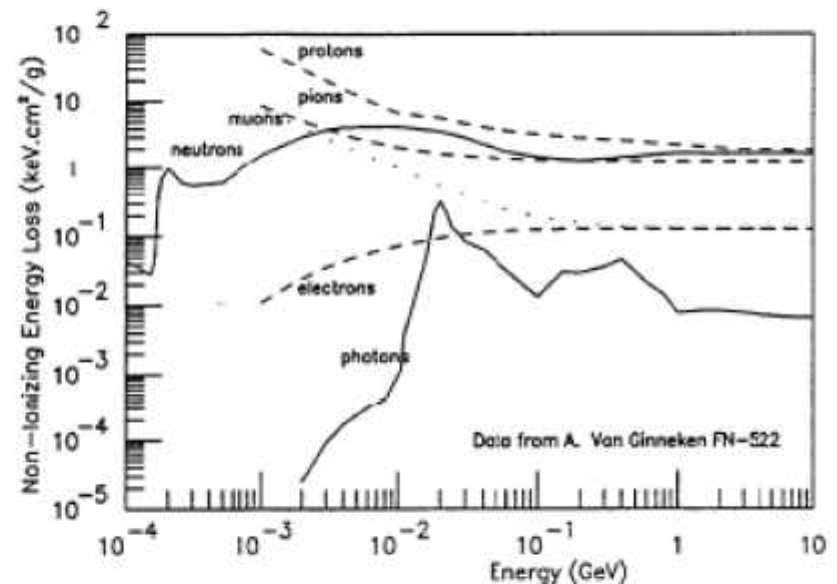


Bulk damage and NIEL function

Bulk damage scales linearly with the amount of Non Ionizing Energy Loss (NIEL hypothesis), which is very dependent on the particle type and its energy



A. Vasilescu, Fluence normalization based on the NIEL scaling hypothesis, 3rd ROSE Workshop on Radiation Hardening of Silicon Detectors, DESY Hamburg 12-14 February 1998, DESY-PROCEEDINGS-1998-02.



A. Van Ginneken, Fermilab Note, FN-522 (1989).

$\text{NIEL}(1 \text{ MeV gamma}) \sim 10^{-5} * \text{NIEL}(1 \text{ MeV neutron})$

Bulk damage effects

Increase of the dark current generated in the silicon bulk

$$I = \alpha \Phi_{\text{eq}} V$$

Φ_{eq} – 1 MeV neutron equivalent total flux

V – silicon active volume

α – dark current damage constant ($\sim 4 \cdot 10^{-17}$ A/cm for 1 MeV neutrons after 80 min annealing at 60 °C or $\sim 10^{-16}$ A/cm few day annealing at room temperature)

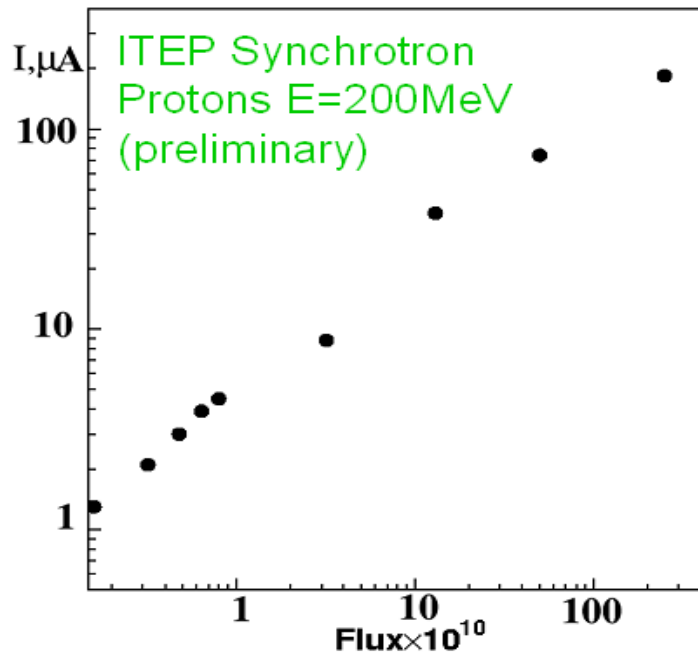
Changes in the effective doping concentration (creation of acceptor-like states) a few weeks after irradiation:

$$\Delta N = N_0(1 - e^{-c\Phi}) + b\Phi$$

where $N_0 = 3.36(\pm 0.03) \times 10^{11} \text{ cm}^{-3}$, $c = 3.58 (\pm 0.2) \times 10^{-13} \text{ cm}^2$, $b = 0.0171(\pm 0.0001) \text{ cm}^{-1}$, and Φ is the total neutron fluence in neutrons/cm².⁵

HERA-B Design Report, DESY-PRC 95/01, 1995.

Radiation damage measurements



MEPhi/PULSAR SiPMs

Dark current increases linearly with flux Φ as in other Si devices:

$$\Delta I = \alpha \Phi V_{\text{eff}} \text{Gain}, \quad \text{where } \alpha = 6 \times 10^{-17} \text{ A/cm}$$

$V_{\text{eff}} \sim 0.004 \text{ mm}^3$ determined from observed ΔI
looks a bit too high
(since it includes SiPM efficiency)
but not completely unreasonable

Since initial SiPM resolution of ~ 0.15 p.e. is much better than in other Si detectors it suffers sooner:
After $\Phi \sim 10^{10}$ individual p.e. signals are smeared out

However MIP signal are seen even after $\Phi \sim 10^{11}/\text{cm}^2$

At ILC neutron flux is much smaller than $10^{10}/\text{cm}^2$ except a small area ($R < 30 \text{ cm}$) around beam pipe

→ Radiation hardness of SiPM is sufficient for HCAL

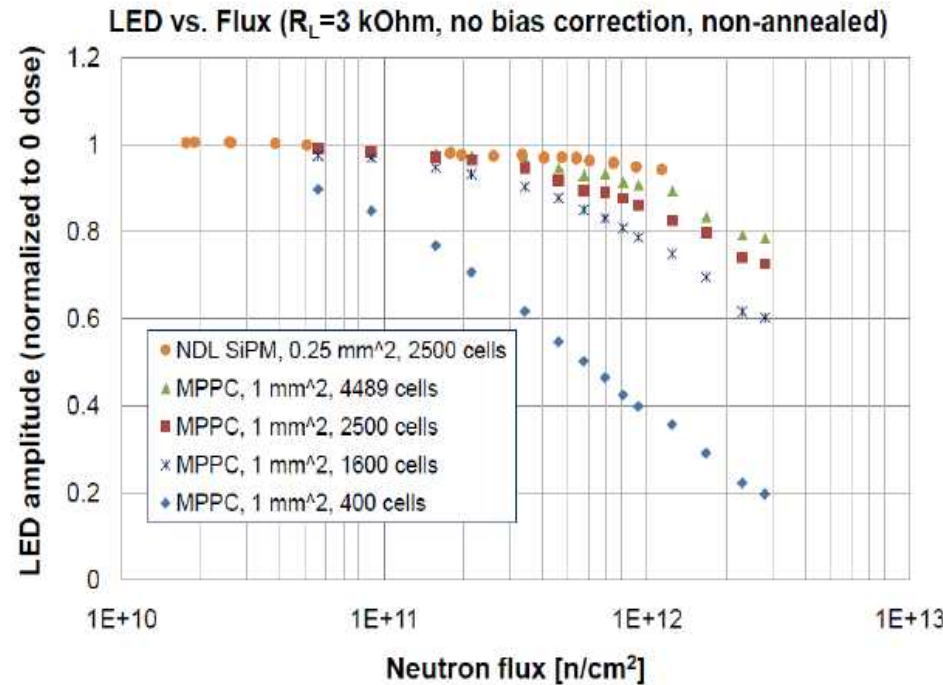
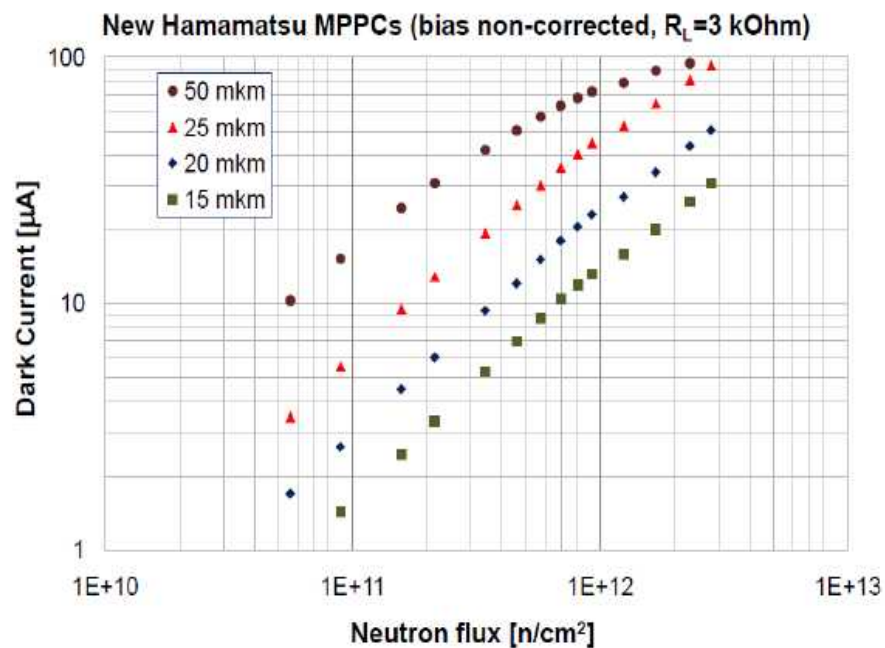
Vienna Conference on Instrumentation 19.02.2007

“A scintillator tile hadron calorimeter prototype with a novel SiPM readout for ILC”

M.Danilov, ITEP, Moscow Representing the CALICE Collaboration

Neutron irradiation tests

We performed SiPMs' radiation hardness tests using neutrons ($E \sim 1$ MeV) at CERN IRRAD-6 facility (see NDIP-2011 talk [A. Heering et al. "Radiation damage studies of silicon photomultipliers at SLHC at CERN PS"](#))



G-APDs with high cell density and fast recovery time can operate up to $3 \cdot 10^{12}$ neutrons/cm² (gain change is $< 25\%$).

SiPM's radiation hardness

212 MeV proton beam at Massachusetts General Hospital.

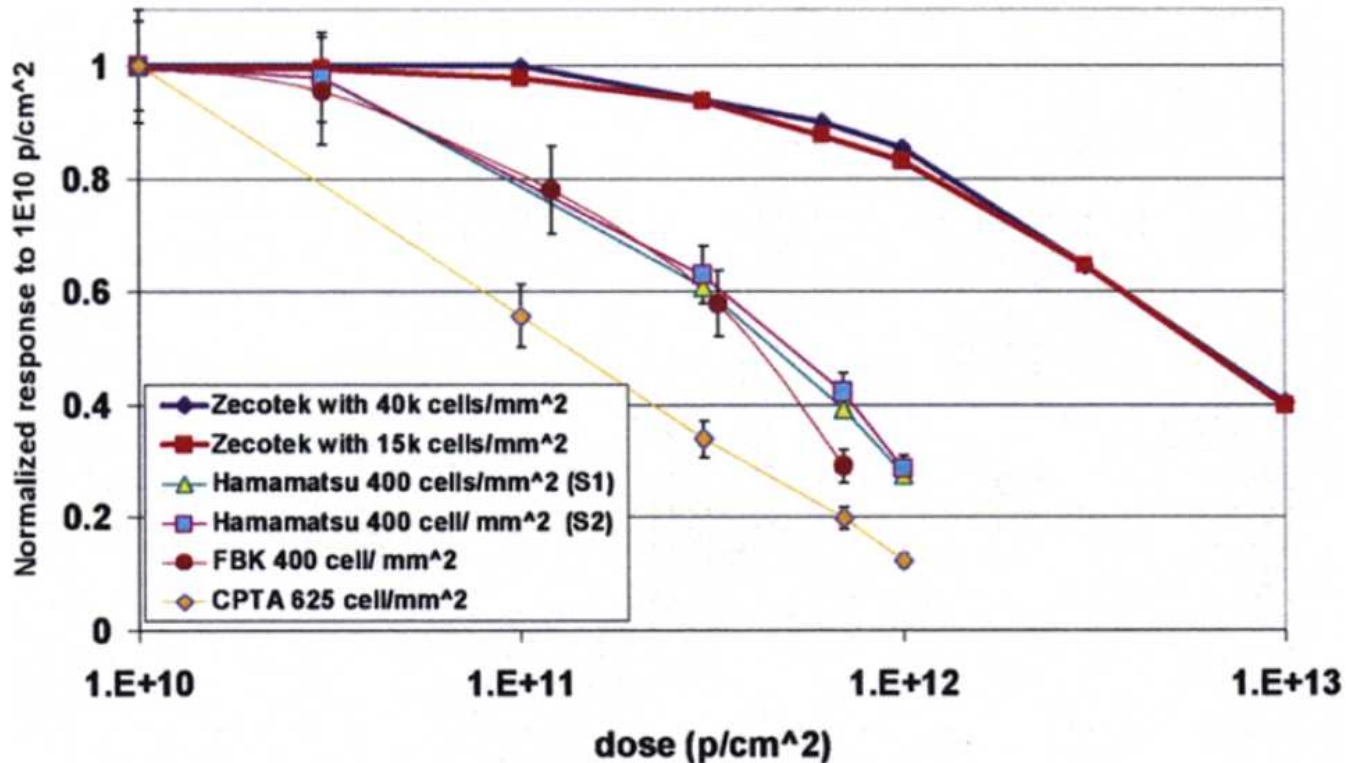


Fig.11. Response vs. radiation fluence for different samples and manufacturers (gain was corrected for voltage drop over the series resistor).

A. Heering et al., Radiation damage studies on SiPMs for calorimetry at the super LHC, IEEE Nuclear Science Symposium Conference Record, vol. 2, 2008.

Chip Name	Measured quantity	Application	Input configuration	Technology
FLC_SiPM	Pulse charge	ILC Analog HCAL	Current input	CMOS 0,8 μm
MAROC	Pulse charge, trigger	ATLAS luminometer	Current input	SiGe 0,35 μm
SPIROC	Pulse charge, trigger, time	ILC HCAL	Current input	SiGe 0,35 μm
NINO	Trigger, pulse width	ALICE TOF	Differential input	CMOS 0,25 μm
PETA	Pulse charge, trigger, time	PET	Differential input	CMOS 0,18 μm
BASIC	Pulse height, trigger	PET	Current input	CMOS 0,35 μm
SPIDER (VATA64-HDR16)	Pulse height, trigger, time	SPIDER RICH	Current input	
RAPSODI	Pulse height, trigger	SNOOPER	Current input	CMOS 0,35 μm

<http://indico.cern.ch/contributionListDisplay.py?confId=117424>

Chip Name	# of channels	Digital output	Power supply	Area [sq mm]	Dynamic range	Input resistance	Timing jitter	Year
FLC_SiPM	18	n	5V (0,2W)	10			-	2004
MAROC2	64	y	5 V	16	80 pC	50 Ω		2006
SPIROC	36	y	5 V	32				2007
NINO	8	n	(0,24W)	8	2000 pe	20 Ω	260 ps	2004
PETA	40	y	(1,2W)	25	8 bit		50 ps	2008
BASIC	32	y	3,3 V	7	70 pC	17 Ω	~120 ps	2009
SPIDER (VATA64-HDR16)	64	n		15	12 pC			2009
RAPSODI	2	y	3,3 V (0,2W)	9	100 pC	20 Ω	-	2008

<http://indico.cern.ch/contributionListDisplay.py?confId=117424>

Summary

- SiPMs are very promising, fast developing new solid state photodetectors
- Photon detection efficiency at the level of PMT and higher
- A lot of different variations concerned to SiPMs parameters and casings
- SiPMs are commercially available already

Backup slides

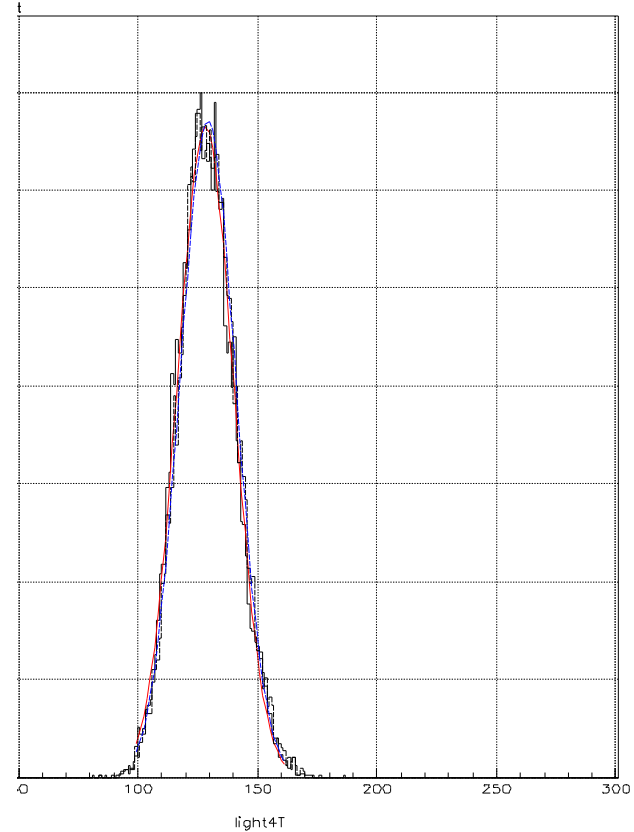
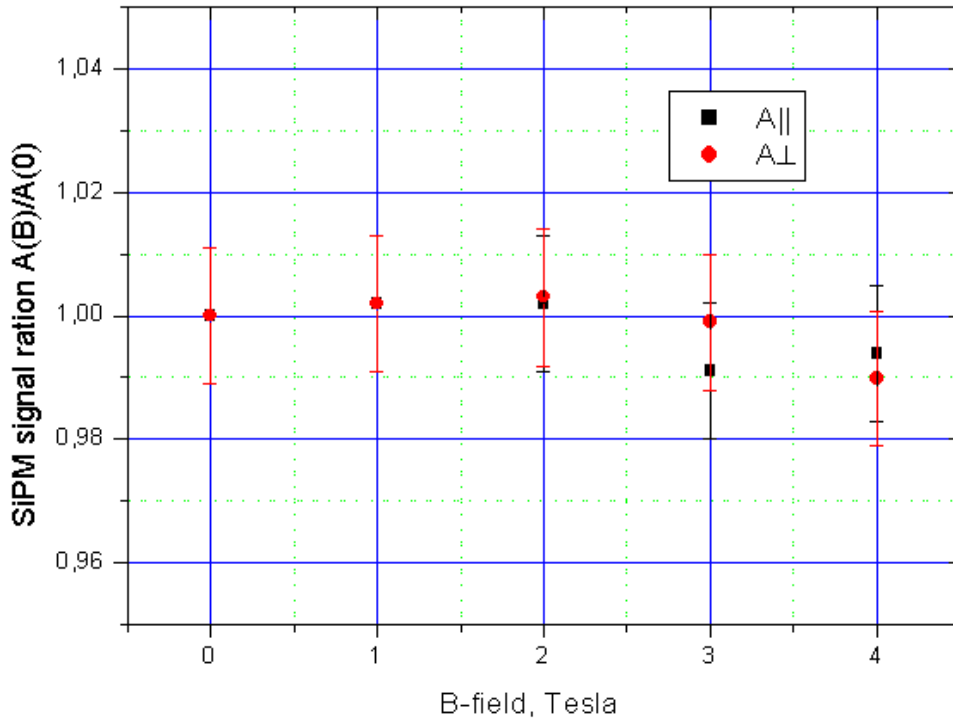
Comparison of the SiPM characteristics in magnetic field of $B=0\text{T}$ and $B=4\text{T}$

(very preliminary, DESY March 2004)

LED signal ~ 150 pixels

$$A=f(G, \epsilon, x)$$

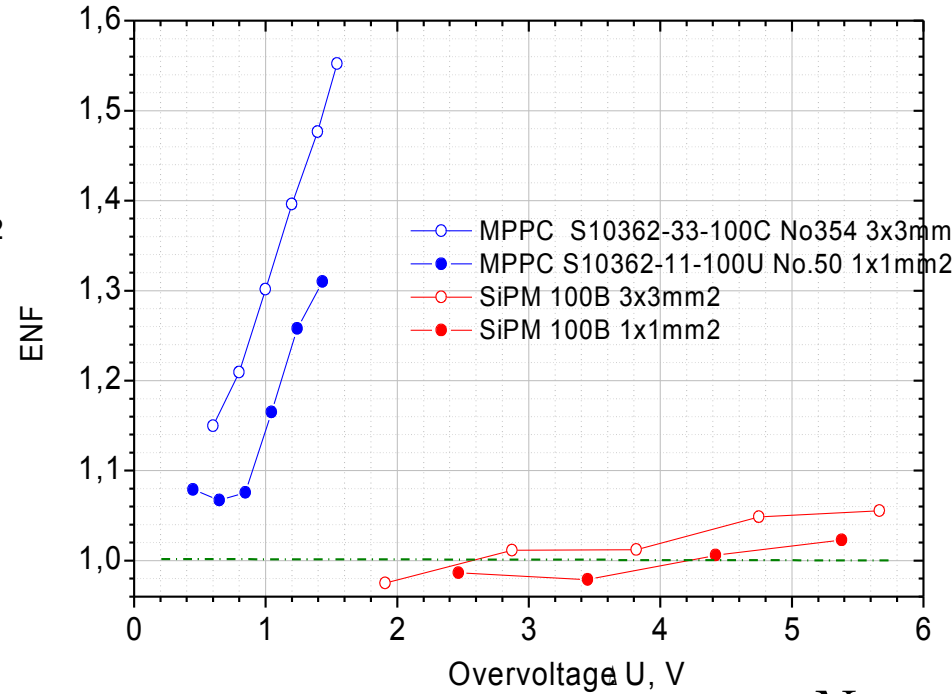
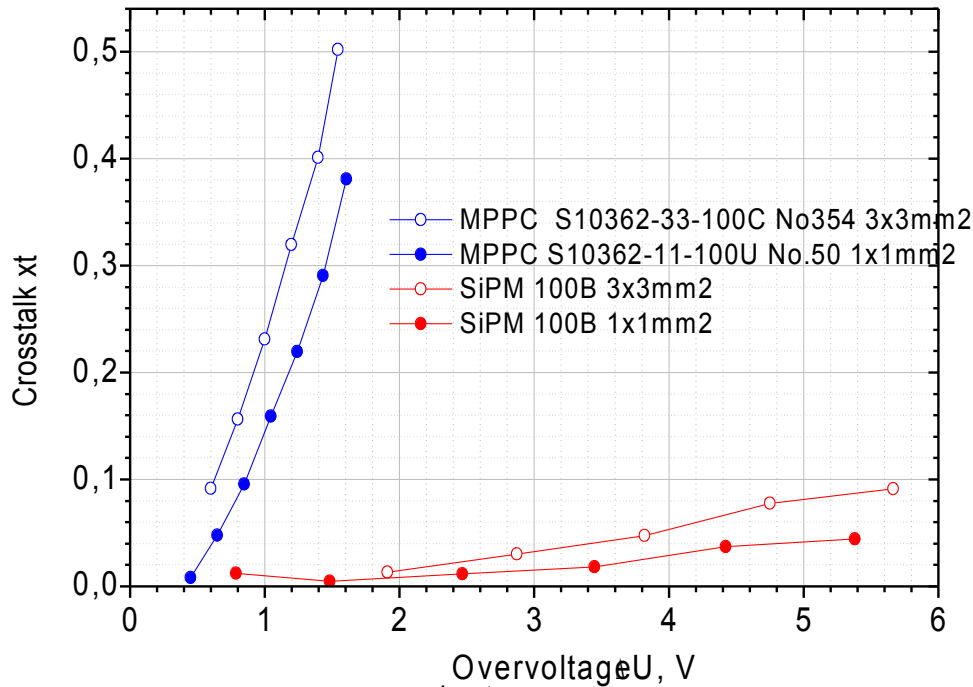
2004/03/28 17.42



No Magnetic Field dependence at 1% level

Crosstalk and Excess noise factor

For light distributed according to Poisson law



$$ENF \equiv \left(\frac{\sigma_{out} / A_{out}}{\sigma_{in} / A_{in}} \right)^2$$

$$ENF = N_0 \cdot \left(\frac{\sigma}{\langle Mean \rangle} \right)_{\text{exper}}^2$$

$$N_{\text{fired_pixels}} = \frac{N_0}{1 - xt}$$

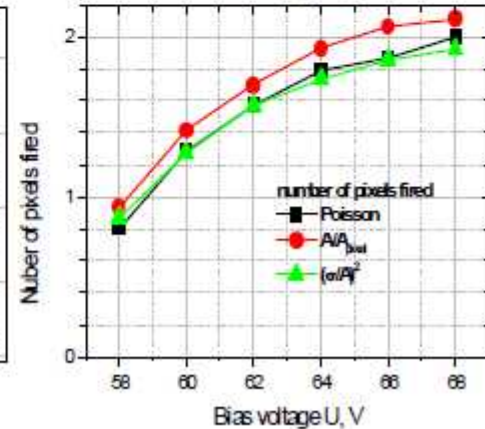
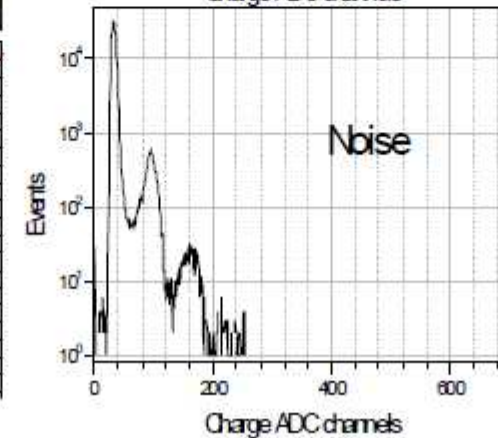
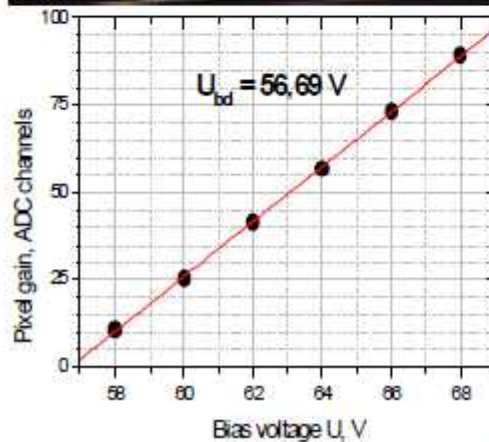
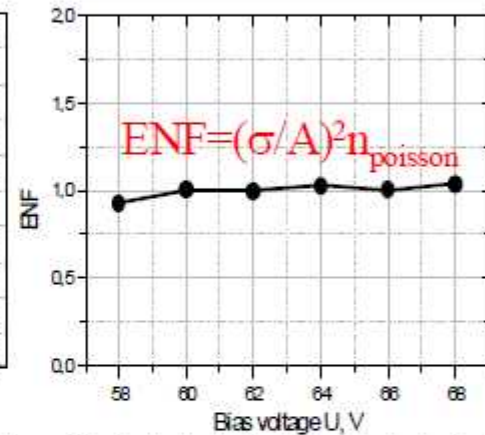
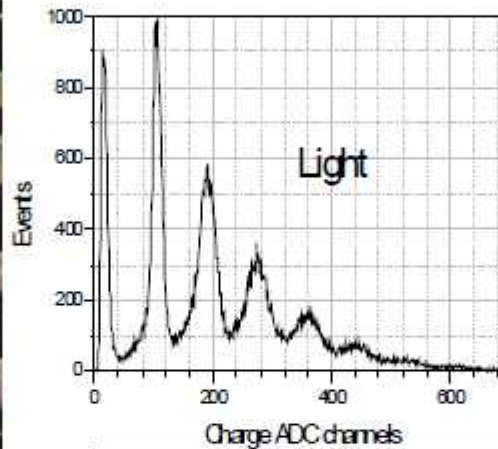
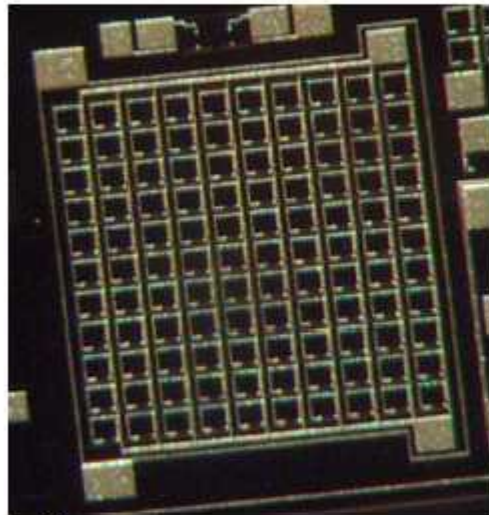
$$N_{\text{fired_pixels}} = \frac{\langle Mean \rangle}{A_{1e}}$$

N_0 initially fired pixels calculated from “0” probability

Xt crosstalk

A_{1e} amplitude of single pixel

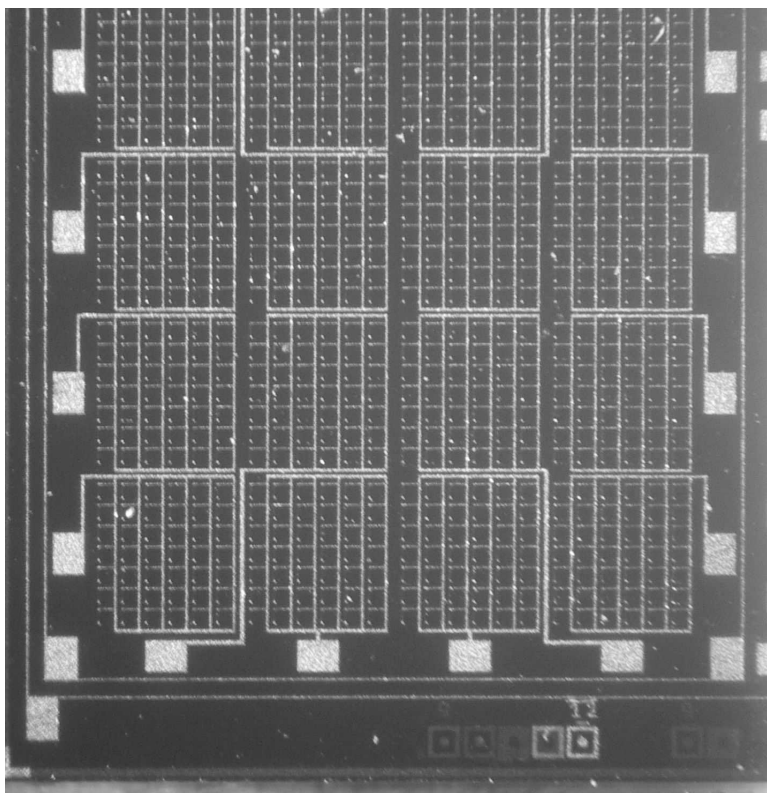
First step: SiPM 1.4x1.4 mm² with OC suppression topology



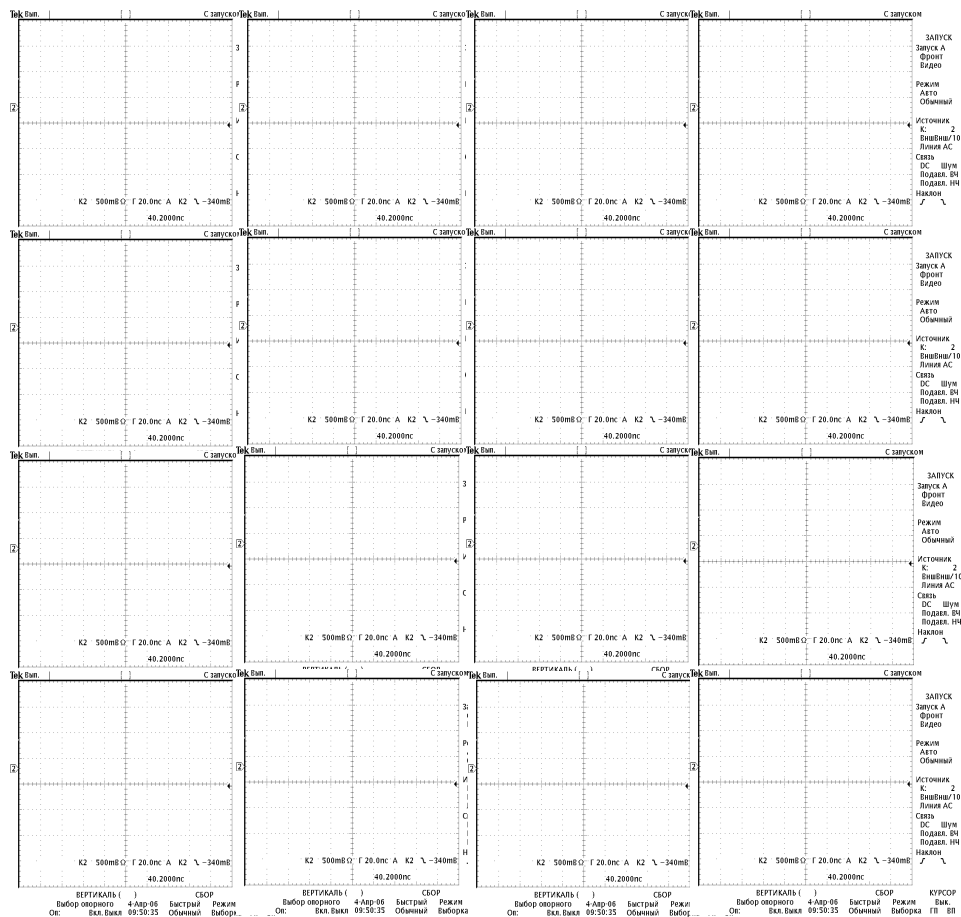
SiPM matrix

For some applications is very attractive to use monolithic SiPM matrix

- For decreasing of light losses
- For position sensitivity
- For fast readout



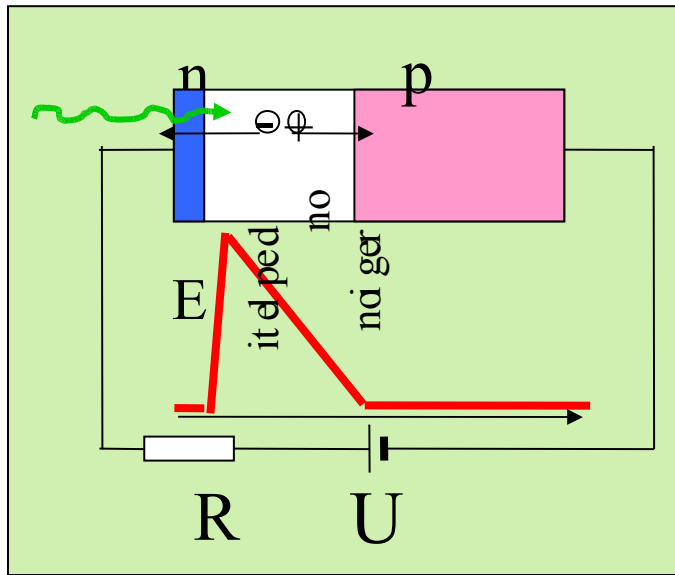
Common bias voltage $U=57.8B$



16 SiPMs in matrix
Elena Popova, MEPhI
SiPM 0.75x0.75mm²

DITANE ST DESY K-7 Dec 2011
Signals on scope from LED pulses

p-n-junction based detectors



Impact Ionization

Avalanche multiplication

Geiger discharge

Geiger mode features

Output signal doesn't depend from input

Output signal value Q is determined by charge accumulated on pixel capacitance

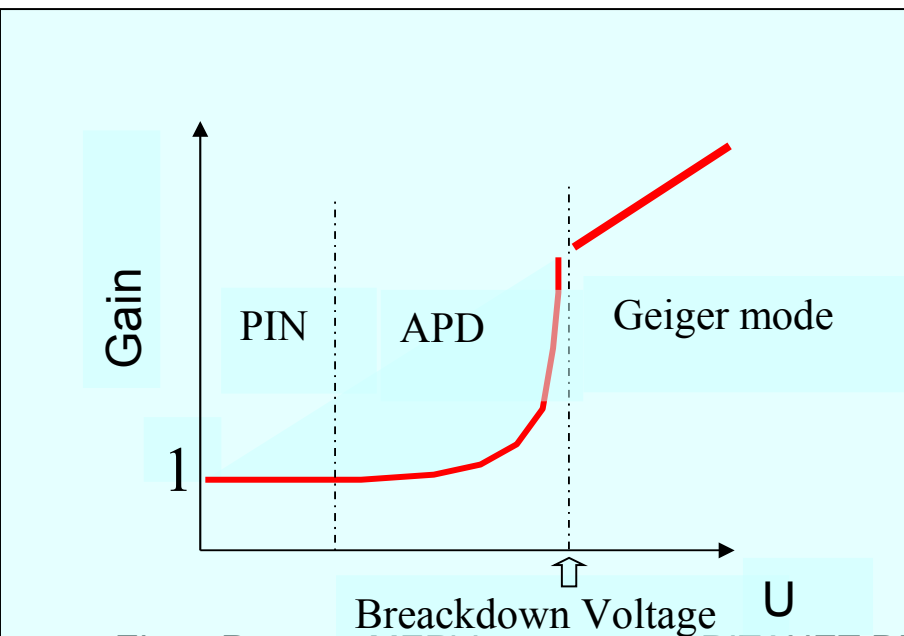
$$Q = C_{\text{pixel}} \cdot (V - V_{\text{breakdown}})$$

$$M = Q/e - \text{pixel gain}$$

$$M = 10^6 - 10^7$$

Discharge duration – of about 1 ns

(selfquenching due to resistor)

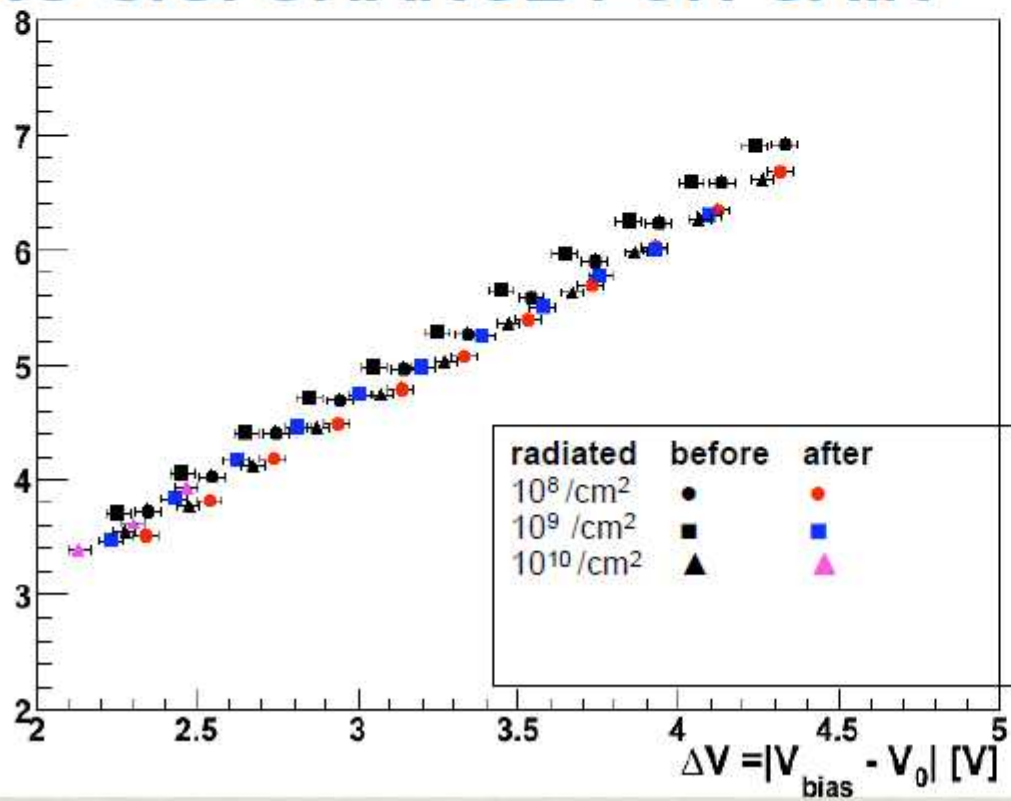


radiation tolerance of MPPC

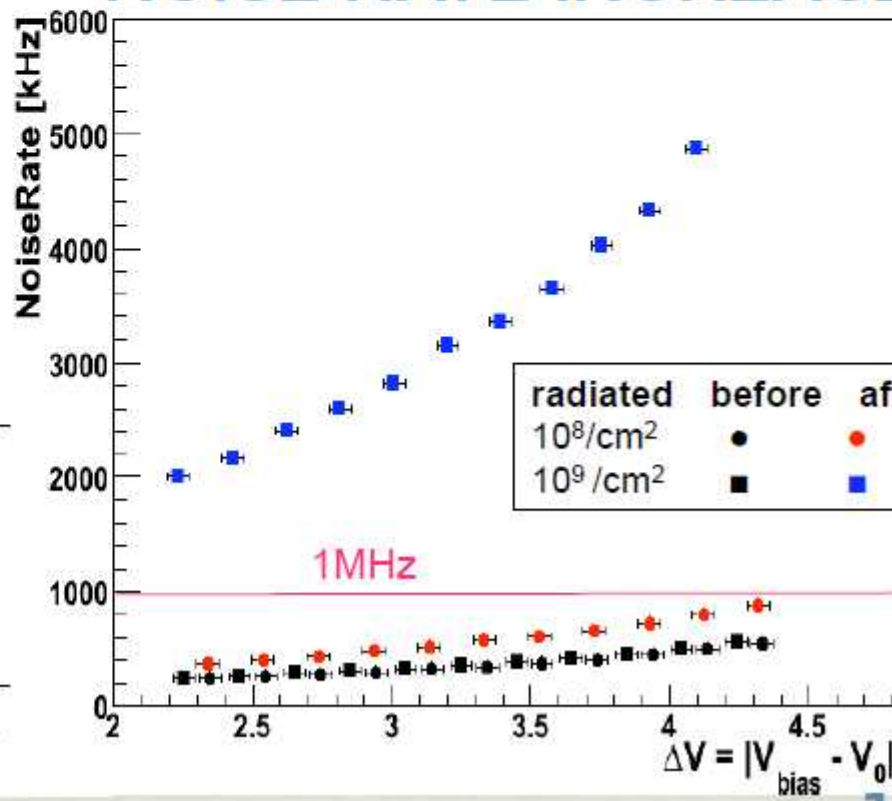
* **neutron** irradiation
by reactor

$10^8-10^{10} / \text{CM}^2$

NO SIG. CHANGE FOR GAIN



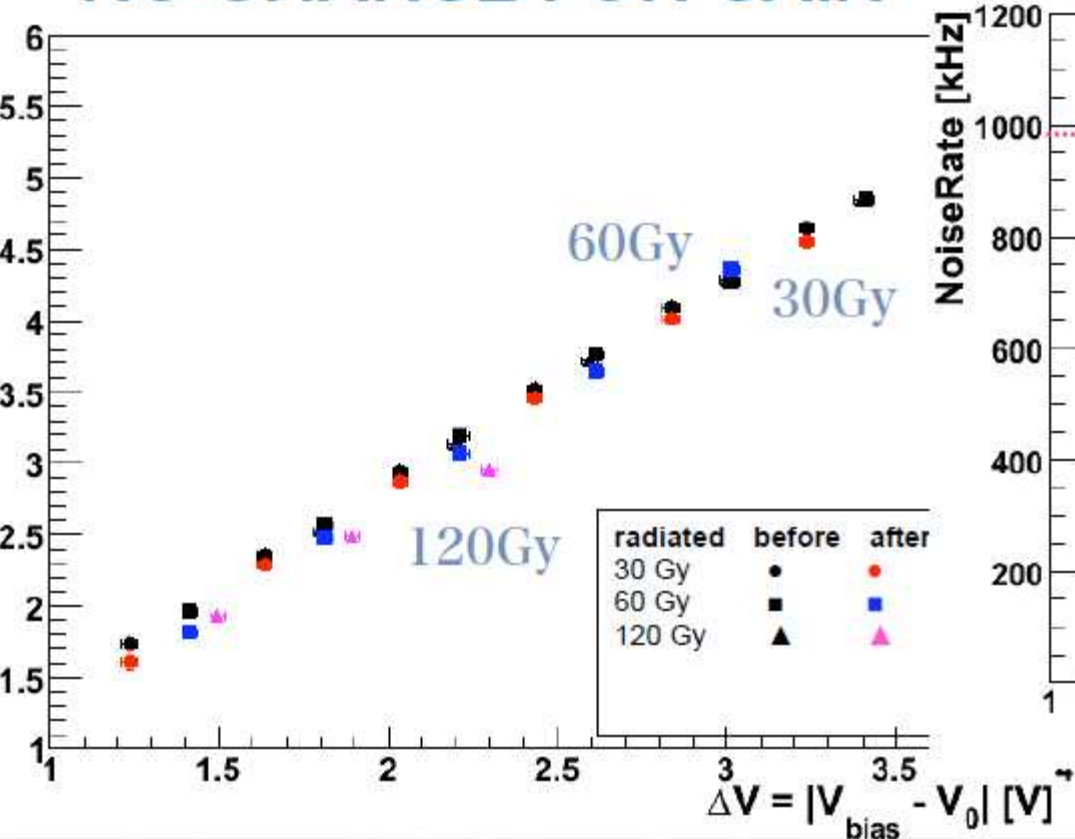
NOISE RATE INCREASE



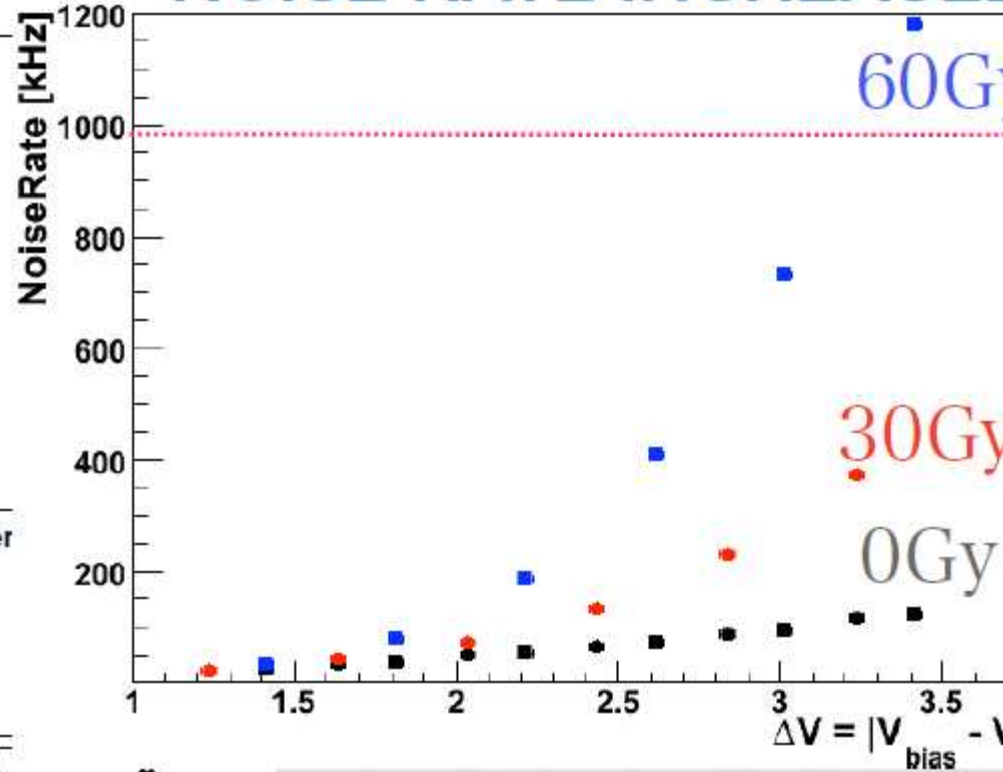
radiation tolerance of MPPC

* **gamma** irradiation ^{60}Co

NO CHANGE FOR GAIN



NOISE RATE INCREASED





Dark rate increase per $1E10$ n/cm²



						24C	20C	annealing (2.5)	
	$\Delta I / 1E10$ (uA/cm ²)	A(mm ²)	ΔV (V)	PDE 520 nm	Gain at dV (*1E6)	Δ rate (Mhz/mm ²)1E10			thickness (um)
Zecotek	1.6	9	2.0	0.25	0.06	18.5	13.2	5.3	2.4
HPK 50 um	5.3	1.7	1.0	0.25	0.75	26.0	18.6	7.4	3.4
HPK 15 um	0.4	1	2.3	0.09	0.13	20.0	14.3	5.7	2.6
FBK (HG)	30	6	2	0.12	0.90	34.7	24.8	9.9	4.5
FBK (LG)	25	6	2	0.07	0.60	43.4	31.0	12	5.7
NDL	1.0	0.25	2.5	0.07	0.10	250.0	179	71	33
KETEK	7.8	1	1.9	0.14	1.40	34.8	24.9	9.9	4.5
HPK APD	0.15	25		0.85	0.0003	125.0	89.3	36	16